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# X-ray Diffractometer

Pecharsky Chapter 6

Cullity Chapter 1

Krawitz Chapter 3

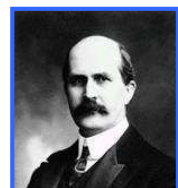
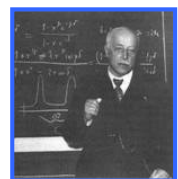
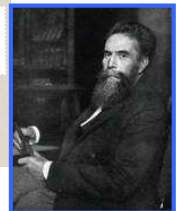
Jenkins & Snyder - Chapter 1, 4, 5, 6

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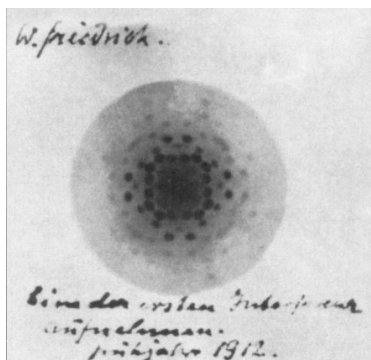
## X-ray

- W.C. Röntgen
  - ✓ 1895: Discovery of X-ray
  - ✓ 1901: First Nobel prize for Physics
- M.T.F. von Laue
  - ✓ 1912: X-ray diffraction, in cooperation with Friedrich and Knipping
  - ✓ Laue equation, Laue reflections
  - ✓ 1914: Nobel prize for Physics
- C.G. Darwin
  - ✓ 1912: Dynamical scattering theory
  - ✓ Darwin width
- W.H. and W.L. Bragg
  - ✓ 1914: X-ray diffraction from powder samples
  - ✓ Bragg's equation, Bragg reflections
  - ✓ 1915: Nobel prize for Physics
- P.P. Ewald
  - ✓ 1916: Theoretical description of X-ray diffraction
  - ✓ Ewald construction, reciprocal space



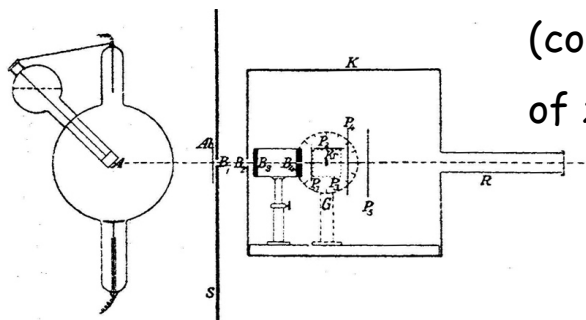
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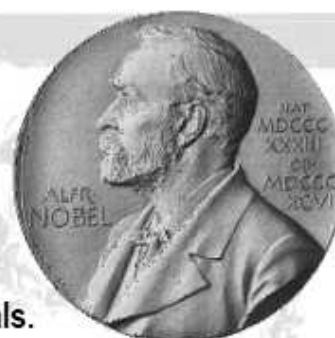
X-ray diffraction pattern of a single crystal of Zinc Blende (ZnS)

Friedrich, Knipping and von Laue, 1912,  
University of Munich

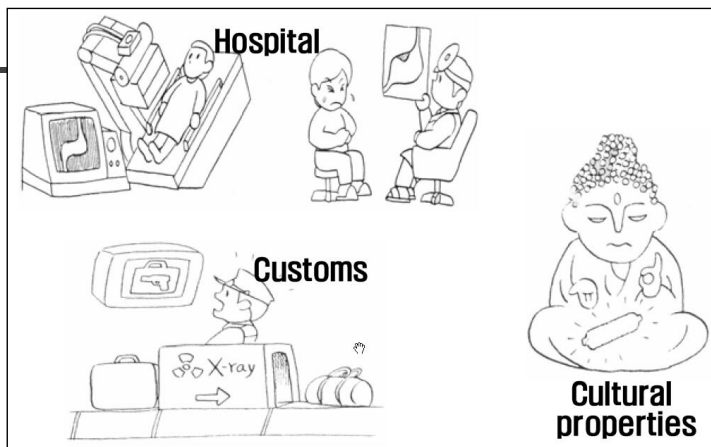


(confirmation of the wave character  
of x-rays)

## Nobel Prizes for Research with X-Rays



- 1901 W. C. Röntgen in Physics for the discovery of x-rays.
- 1914 M. von Laue in Physics for x-ray diffraction from crystals.
- 1915 W. H. Bragg and W. L. Bragg in Physics for crystal structure determination.
- 1917 C. G. Barkla in Physics for characteristic radiation of elements.
- 1924 K. M. G. Siegbahn in Physics for x-ray spectroscopy.
- 1927 A. H. Compton in Physics for scattering of x-rays by electrons.
- 1936 P. Debye in Chemistry for diffraction of x-rays and electrons in gases.
- 1962 M. Perutz and J. Kendrew in Chemistry for the structure of hemoglobin.
- 1962 J. Watson, M. Wilkins, and F. Crick in Medicine for the structure of DNA.
- 1979 A. McLeod Cormack and G. Newbold Hounsfield in Medicine for computed axial tomography.
- 1981 K. M. Siegbahn in Physics for high resolution electron spectroscopy.
- 1985 H. Hauptman and J. Karle in Chemistry for direct methods to determine x-ray structures.
- 1988 J. Deisenhofer, R. Huber, and H. Michel in Chemistry for the structures of proteins that are crucial to photosynthesis.



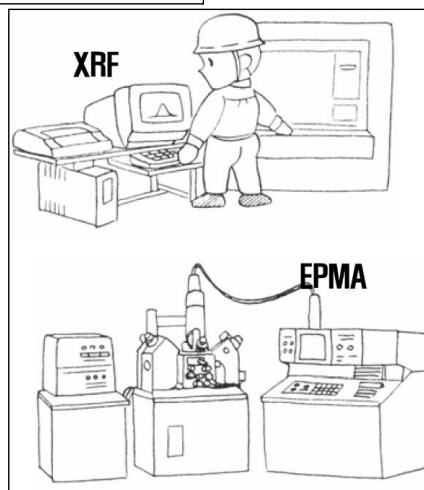
## X-ray Transmission

XRF;  
X-ray fluorescence spectroscopy

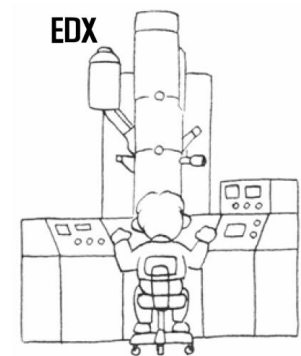
EPMA;  
electron probe micro analyzer

EDX;  
energy dispersive X-ray analyzer

## X-ray Fluorescence



XRF: X-Ray Fluorescence Spectroscopy  
EPMA: Electron Probe Micro Analyzer  
EDX: Energy Dispersive X-ray analyzer



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## Characteristics of X-rays

- Electromagnetic wave; wavelength  $0.3\text{\AA} \sim 3\text{\AA}$ 
  - ✓ Strong penetration through matters
  - ✓ Invisible in air
  - ✓ No interaction with electric and magnetic field
- Photographic → detection
- Fluorescent (e.g. on ZnS, CdS, NaI, etc.) → detection
- Ionizing → detection
- Diffraction ← wavelength  $\sim$  atomic distance
- Transmission → medical, nondestructive evaluation (NDE)

Wavelength  
 $\approx$   
Object Size  
 $\approx$   
Angstroms  
for Condensed  
Matter Research

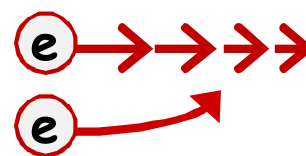
$$\lambda[\text{\AA}] = \frac{12.398}{E_{\text{ph}}[\text{keV}]}$$

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## Generation of X-rays

- X-rays are produced when any electrically charged particle of sufficient kinetic energy rapidly decelerates

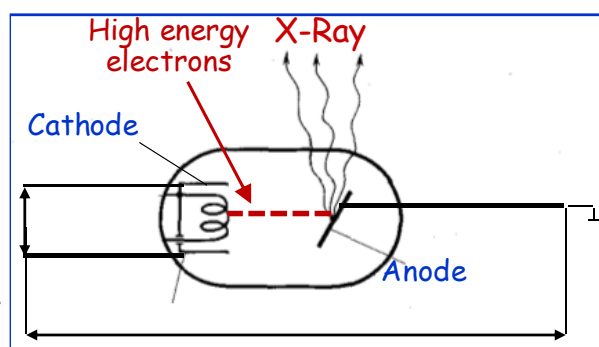
- ✓ change of speed of matter
- ✓ change of direction of movement



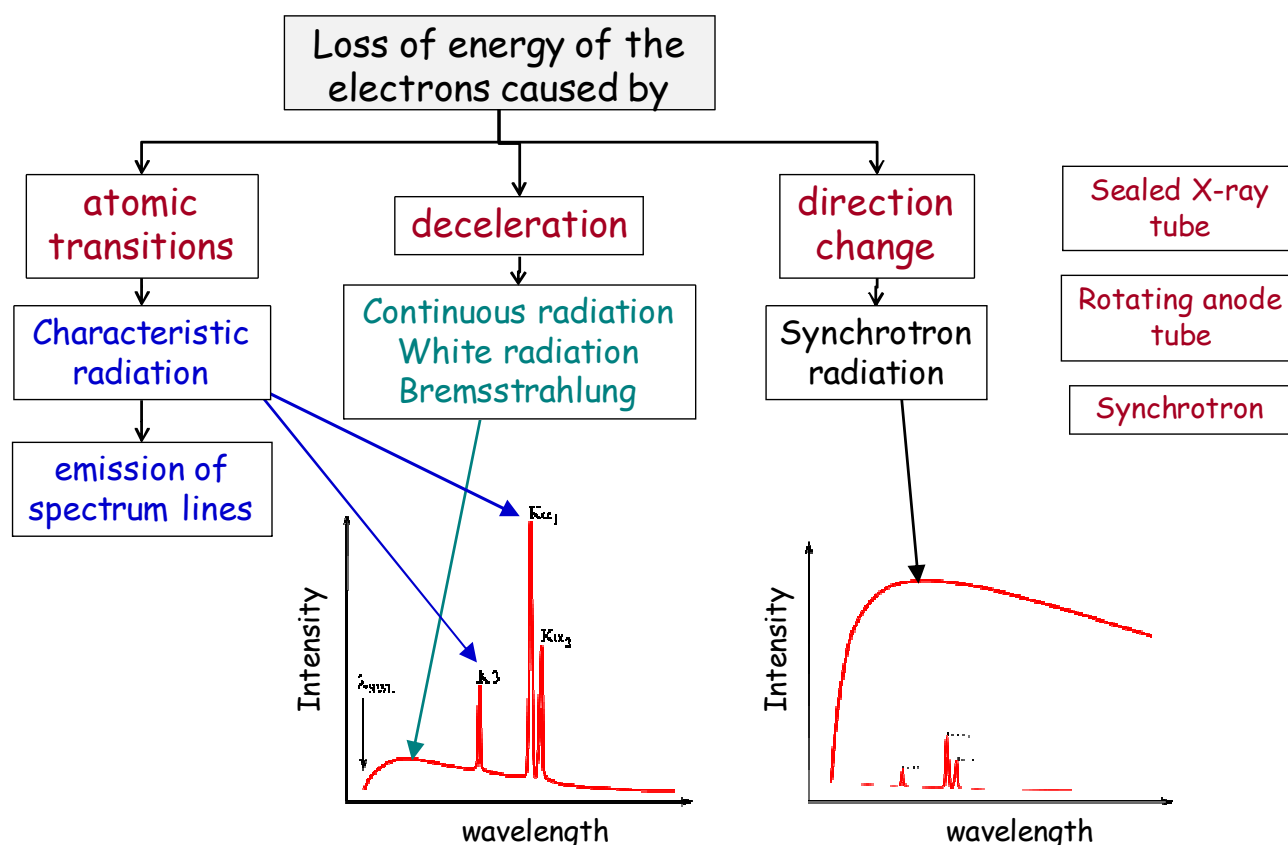
- Bombardment of a target by electrons
- Anode (Cu, Mo, W, Ag ..), Cathode (W, LaB6)
- $10^{-3} \sim 10^{-4}$  Torr chamber, high voltage (10 ~ 50kV)



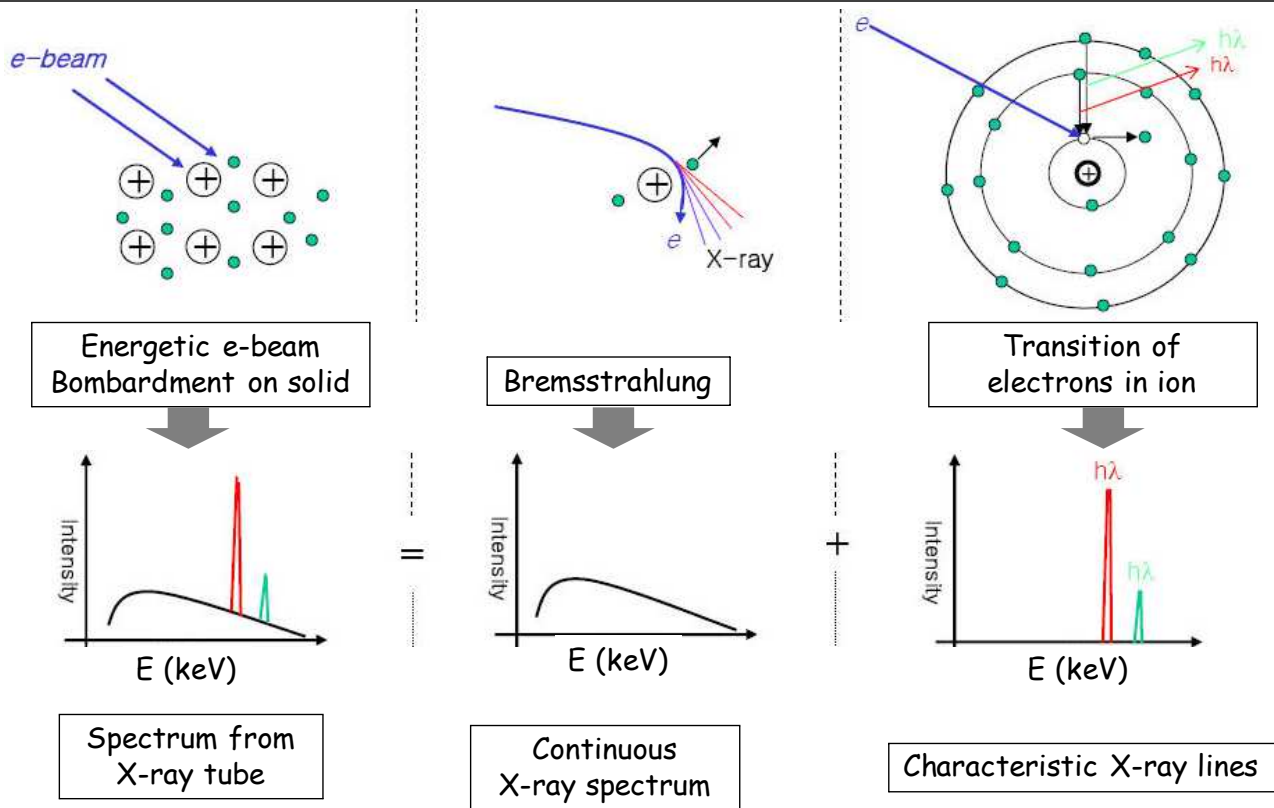
Sealed X-ray tube



## Generation of X-rays

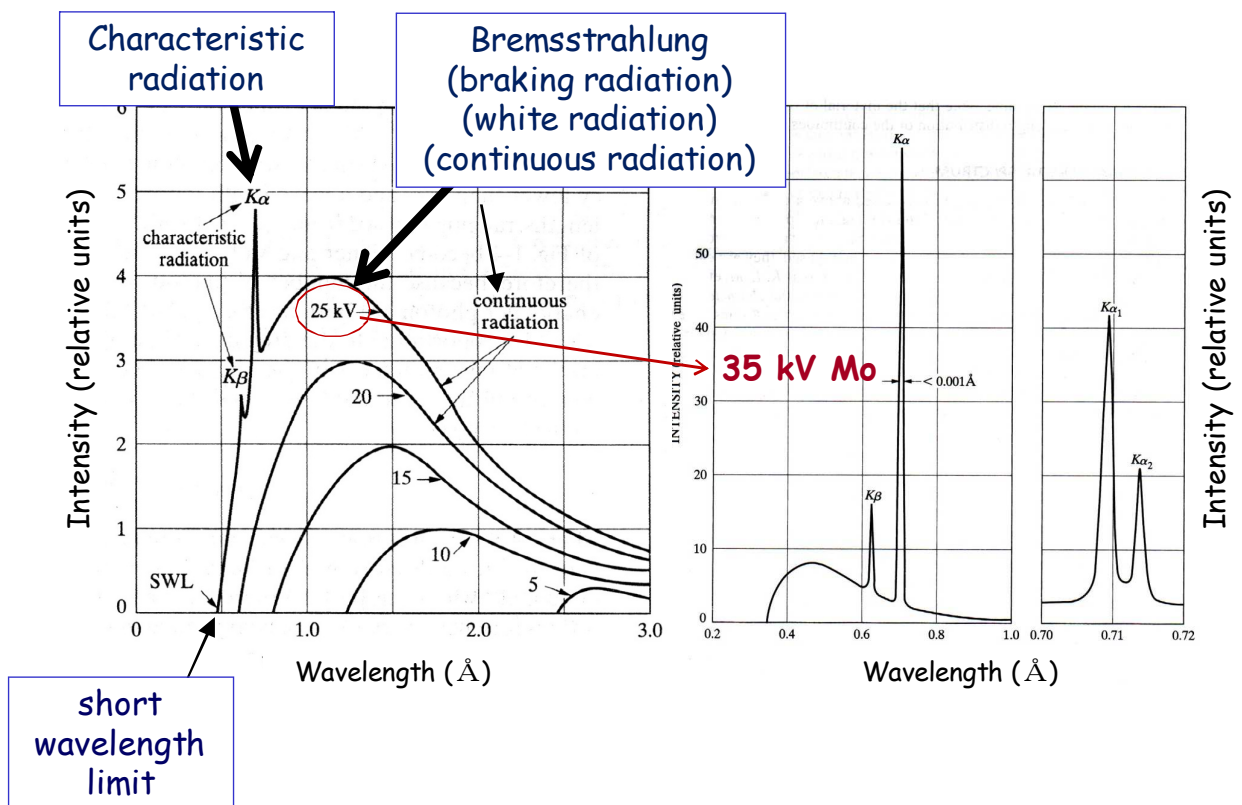


# Generation of X-rays



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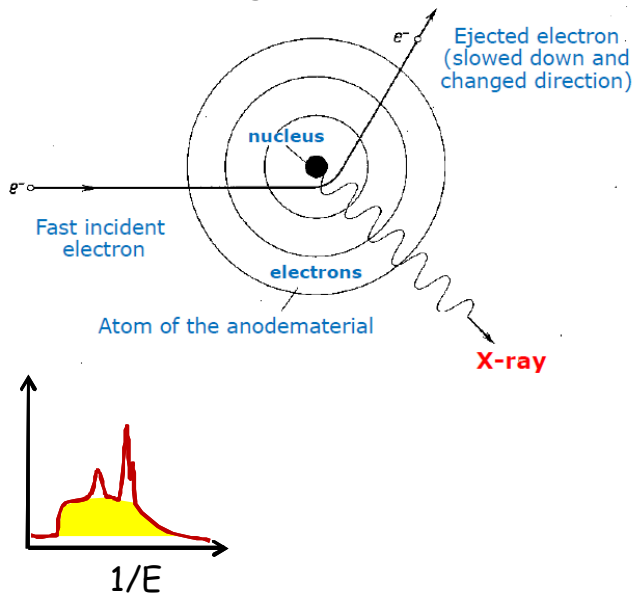
## X-ray spectrum of molybdenum



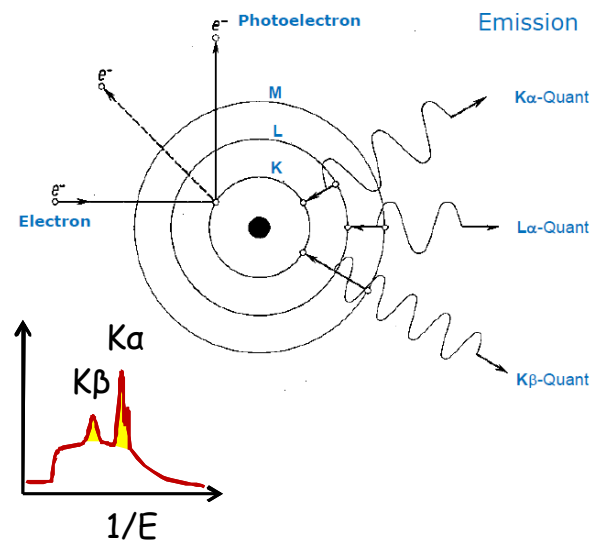


# X-ray Generation

## "Bremsstrahlung" Radiation



## Characteristic Radiation

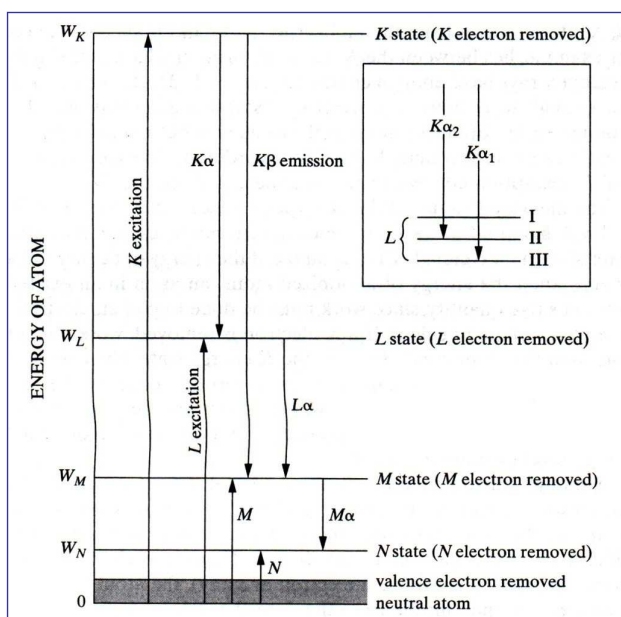


## Cross Sections of Excitation

$$K_{\alpha 1} : K_{\alpha 2} : K_{\beta} = 10 : 5 : 2$$



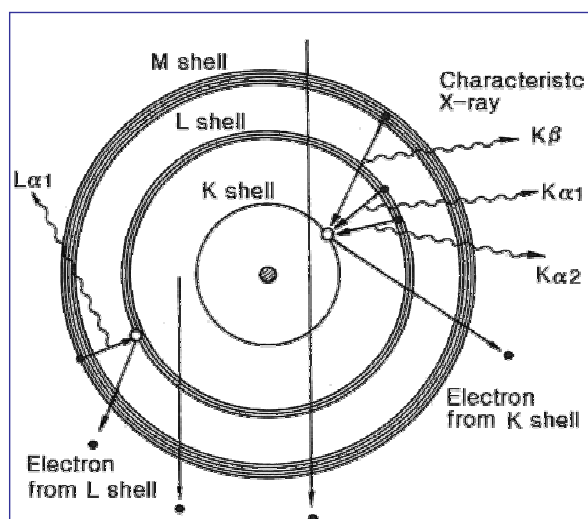
## Atomic energy level



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$$K_{\alpha} = (2K_{\alpha 1} + K_{\alpha 2})/3$$

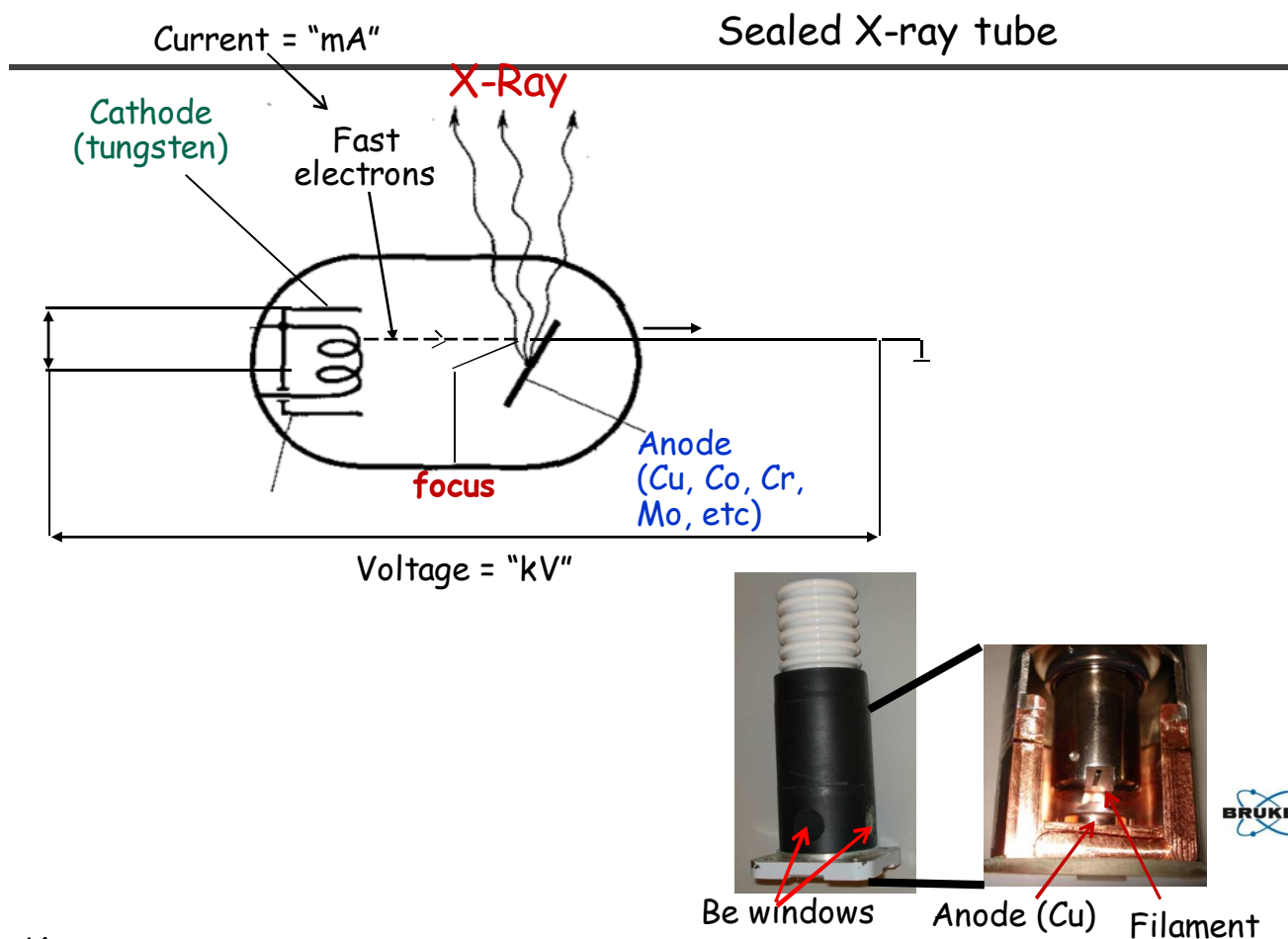
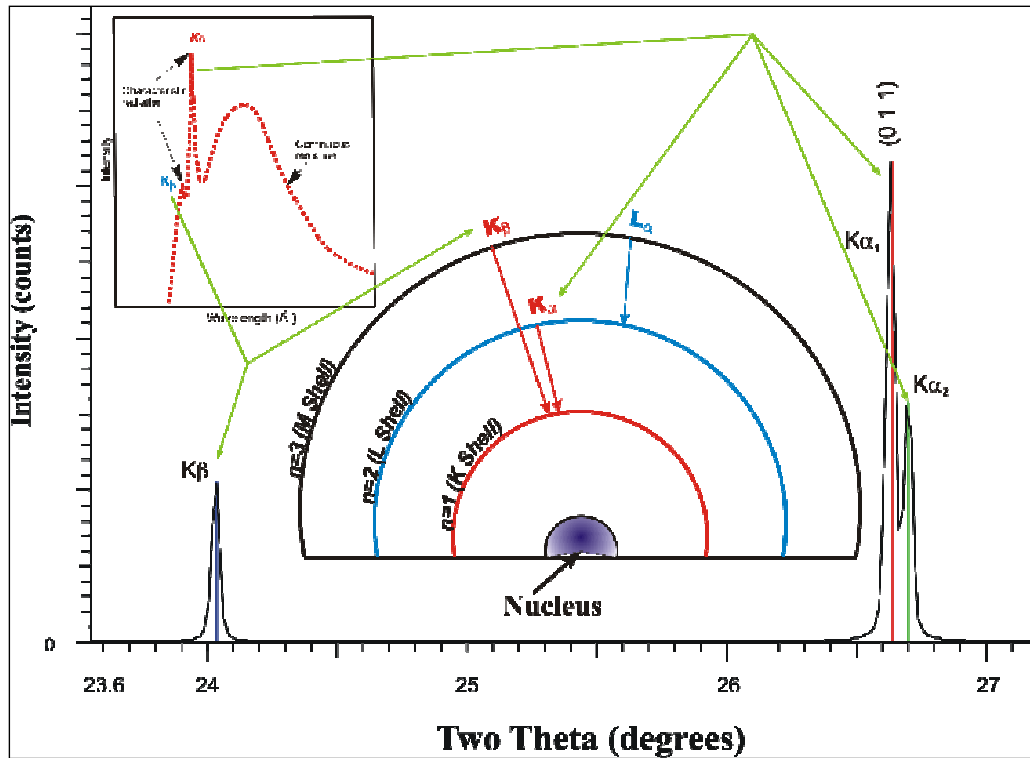
$\beta$ -filter, monochromator



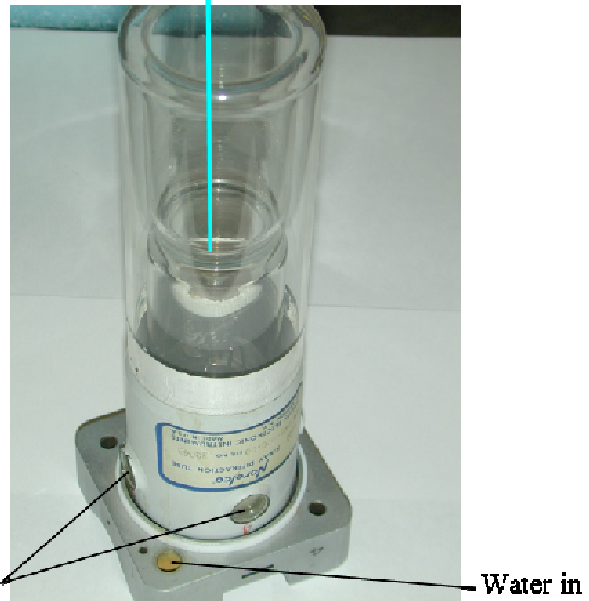
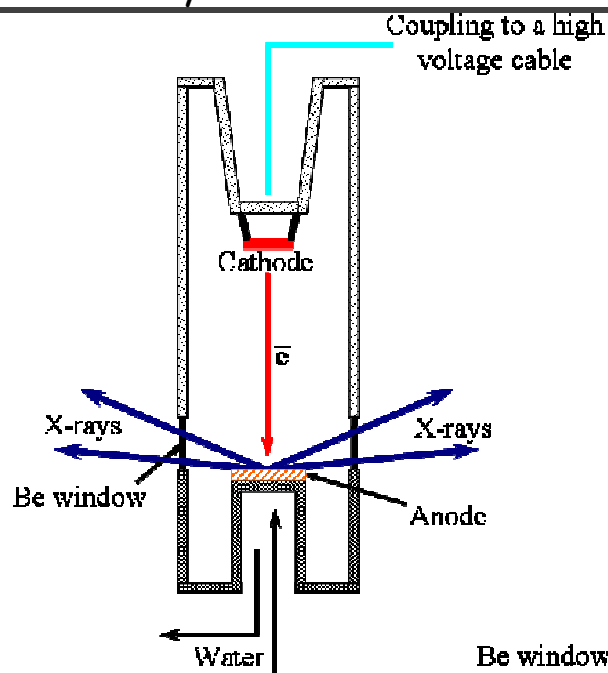
## Intensity ratios

$$K_{\alpha 1} : K_{\alpha 2} : K_{\beta} = 10 : 5 : 2$$

## Characteristic Radiation



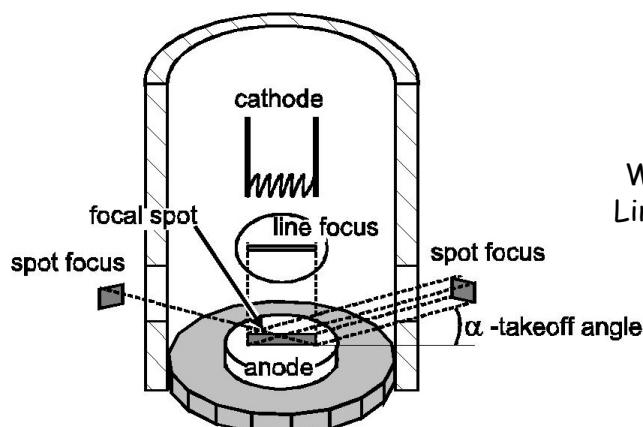
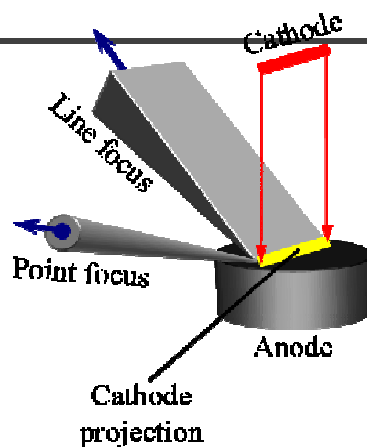
## Sealed X-ray tube



Overall efficiency very low  $\leftarrow$  heat

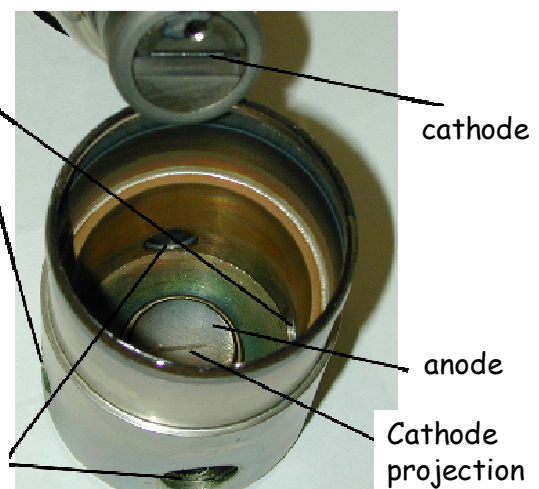
Most of the kinetic energy striking the target is converted into heat  $\rightarrow$   
 $< 1\%$  is transformed into X-ray

## Line focus, Point focus



Windows point focus

Windows Line focus



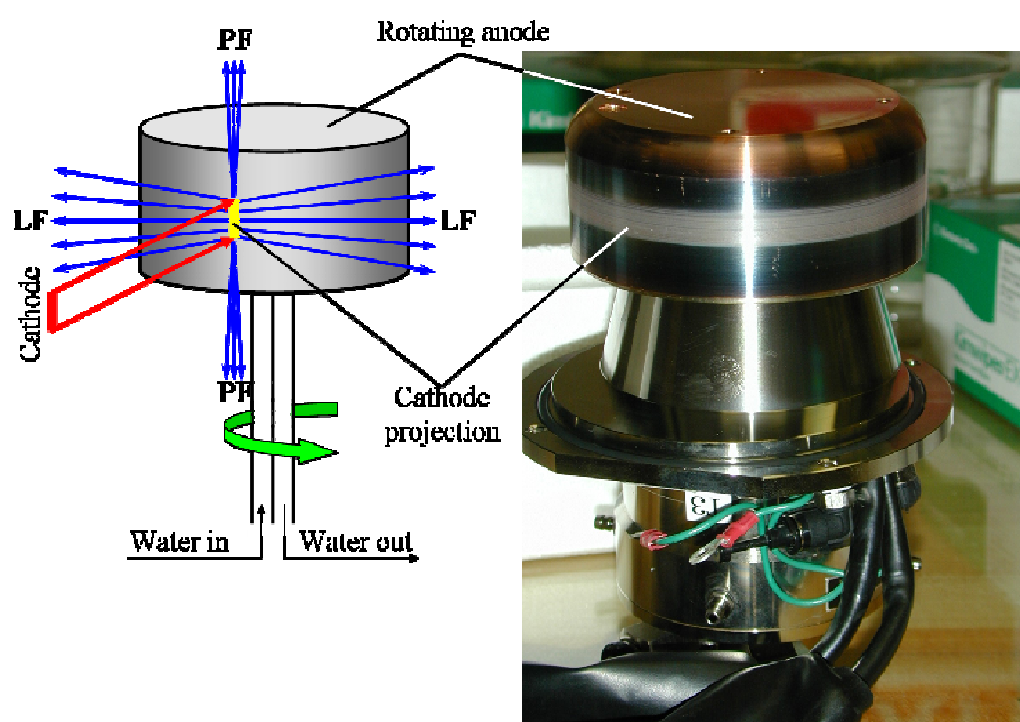


## X-ray from sealed tube

Anode	$K\alpha_1$ (Å)	
Cu	1.54060	- Best for inorganics - Fe and Co fluorescence
Cr	2.28970	- High Resolution for large d-spacing - High attenuation in air
Fe	1.93604	- Used for ferrous alloys to reduce Fe fluorescence - Causes Cr fluorescence
Co	1.78897	- <u>Used for ferrous alloys to reduce Fe fluorescence</u>
Mo	0.70930	- Short wavelength used for small unit cells

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## Rotating anode X-ray source

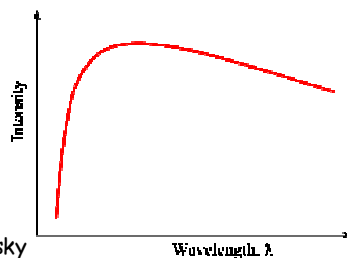
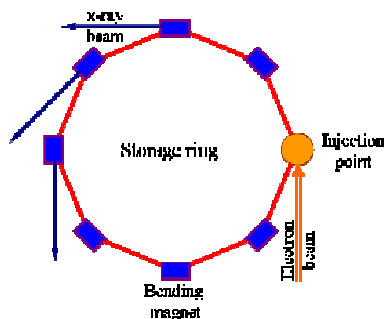


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Pecharsky

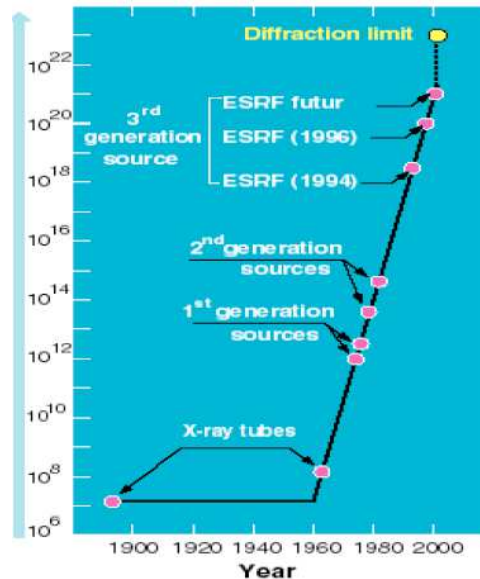
## Synchrotron X-ray

- Most powerful X-ray radiation source
- High brilliance X-ray beam
- Distribution of beam intensity as a function of wavelength

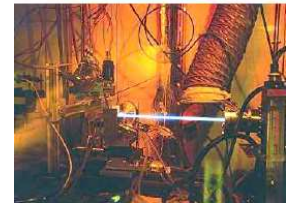


Pecharsky

Brilliance of the X-ray beams  
photons / s / mm<sup>2</sup> / mrad<sup>2</sup> / 0.1% BW )

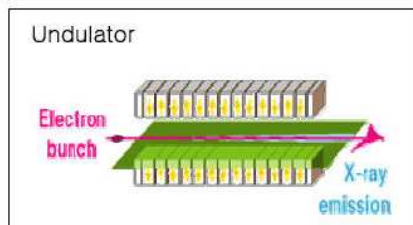
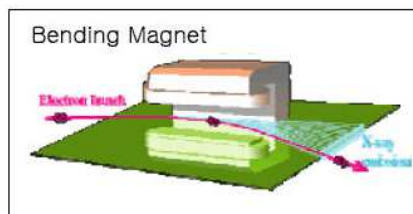


**Intensity !!!**



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## Synchrotron X-ray



### Synchrotron Radiation.

- Very High Dense Source.
- Good Coherent Property.
- Continuous Spectrum.
- Huge Apparatus.

## Brightness & Fluxes for Neutron & X-Ray Sources

	Brightness ( $s^{-1}m^{-2}ster^{-1}$ )	dE/E (%)	Divergence ( $mrad^2$ )	Flux ( $s^{-1}m^{-2}$ )
Neutrons	$10^{15}$	2	$10 \times 10$	$10^{11}$
Rotating Anode	$10^{20}$	0.02	$0.5 \times 10$	$5 \times 10^{14}$
Bending Magnet	$10^{27}$	0.1	$0.1 \times 5$	$5 \times 10^{20}$
Undulator (APS)	$10^{33}$	10	$0.01 \times 0.1$	$10^{24}$

## Neutron diffraction


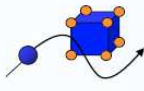
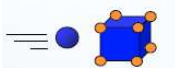


- Produced in nuclear reactors, White spectrum
- Scattered by nuclei (electron clouds in X-ray)
- Scattering factor remains constant over the whole range of Bragg angles
- Scattering factors not proportional to atomic number
- Scattering factors are different for different isotopes of the same element
- Neutrons have spins → interact with unpaired e' spins (magnetic moments), can be used to determine ordered **magnetic structures**

## Electron diffraction

- High vacuum is needed
- e's strongly interact with materials → dynamical theory of diffraction
- Cost of equipment

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## Properties of Neutron


	Mass	No Charge	Spin 1/2 ↑
	No charge	→ Deep penetration	
	Wavelength Å ~ nm (Thermal & Cold Neutron)	→ Atomic & Nanometer scale	
	Energy ~ meV	→ Same magnitude as basic excitations in solids	
	Spin = 1/2	→ Magnetic structure & dynamics	
	Interacts with nuclei	→ Contrast variation ( $b_H = -3.74\text{fm}$ , $b_D = 6.67\text{fm}$ )	

**HANARO at KAERI in Daejeon**

**High-flux Advanced Neutron Application Reactor**


30 MW Multi-purpose Research reactor since 1995

Neutron Scattering, NAA, RI production, Irradiation Test, NTD



RX : Reactor Building    RPF : Radio-Isotope Production Facility  
CNL : Cold Neutron Laboratory    IMEF : Irradiated Material Examination Facility

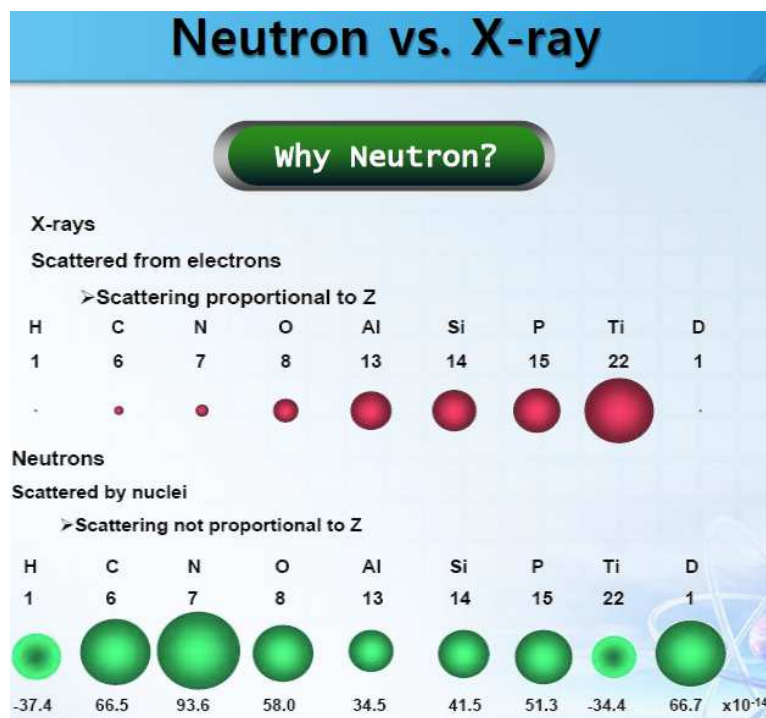
**HANARO Reactor Hall**



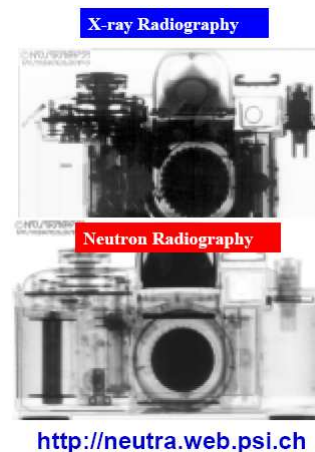
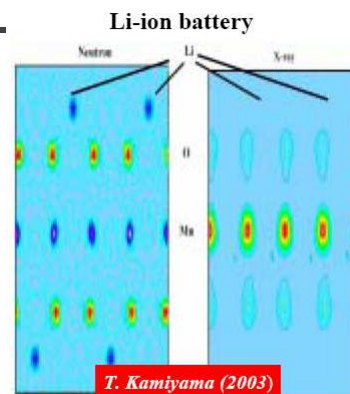
ENF, RSI, Cold Neutron Guide, HRPD, FCD, Bio-D, Bio-C, Th-TAS, NRF

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Presentation of Shin Ae Kim, KAERI



Presentation of Shin Ae Kim, KAERI



## X-ray, neutron, & electron

	X-ray (conv/sync)	Neutron	Electron
nature	wave	particle	particle
medium	atmosphere	atmosphere	high vacuum
Scattering by	e' density	nuclei, magnetic spins of e's	electrostatic potential
Range of $\lambda$ (Å)	0.5~2.5 (0.1~10)	~1	0.01~0.05
$\lambda$ selection	fixed/variable	variable	variable
Lattice image	reciprocal		direct, reciprocal
Direct structure image	no		yes
Applicable theory of diffraction	kinematical		dynamical

- Electric shock
- Radiation hazard
  - ✓ Burns
  - ✓ Radiation sickness
  - ✓ Genetic mutation
- Be window

- Appearance: silvery solid or grey foil  
Melting point: 1278 C      Boiling point: 2970 C
- Very toxic by inhalation - risk of serious damage to health. May act as a human carcinogen for which there is no safe exposure level. May act as a sensitizer.
- Toxicity data    IVN-RAT LD50 0.5 mg kg-1
- Risk phrases    R26 R27 R37 R39.

IVN - intravenous

LD50 - lethal dose 50% kill

R26 - very toxic by inhalation

R27 - very toxic in contact with skin

R37 irritating to respiratory system

R39 - danger of very serious irreversible effects

- No special health risks with Be in solid form

- Skin Contact with Beryllium

- ✓ No effect on contact or temporary embedding.
- ✓ Solvents will not generate beryllium dust, but some acids will. Don't etch beryllium.
- ✓ Wear clean gloves to protect the skin and to protect the beryllium.



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# Collimation

# Monochromatization

# Diffractometer

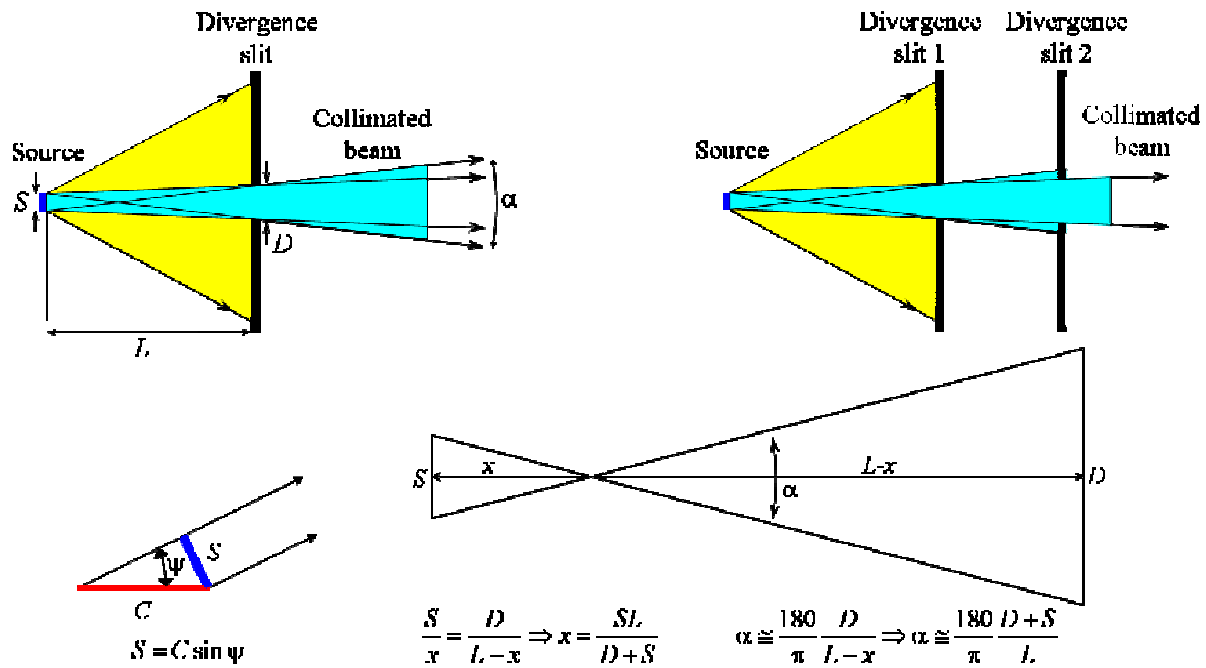


- Conventional X-ray (sealed tube, rotating anode tube) has
  - ✓ Polychromatic nature → monochromatization
  - ✓ Angular divergence → collimation
- 1. White radiation → high background
- 2. Three intense characteristic lines ( $K_{\alpha 1}$ ,  $K_{\alpha 2}$ ,  $K_{\beta}$ ) → three Bragg peaks from each (hkl)
- 3. Angular divergence → broad & asymmetric Bragg peaks
  
- Incident X-ray beam needs to be conditioned to improve the quality of diffraction pattern
- How to reduce both the angular & wavelength dispersion?
- How to reduce both with minimal loss of intensity of incident & diffracted beams?

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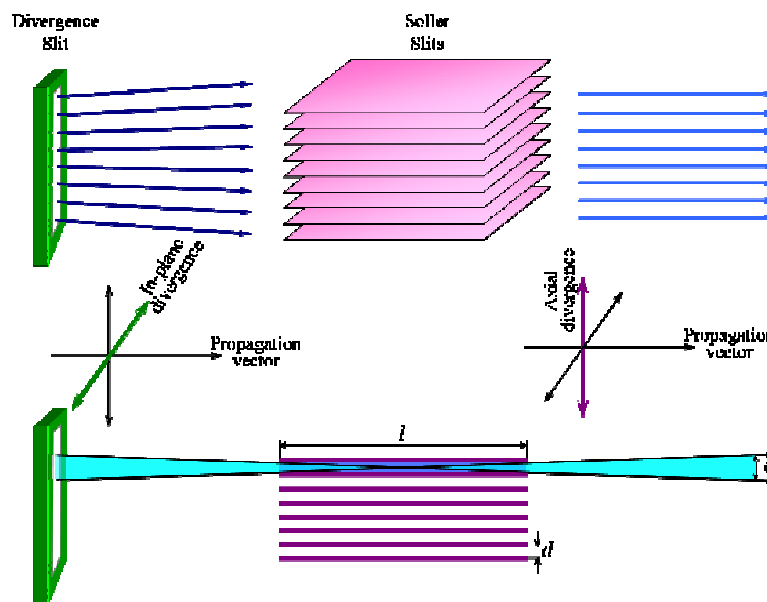
# Collimation slits

## Divergence slit



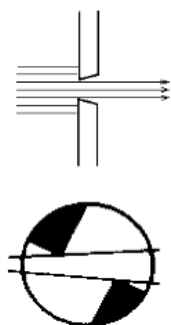
- Reduce angular dispersion of the incident X-ray beam in the plane  $\perp$  to goniometer axis (reduce in-plane divergence)

## Divergence slit & Soller slit

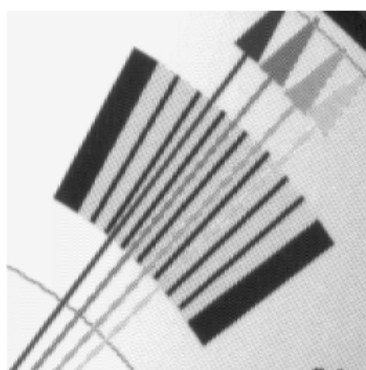
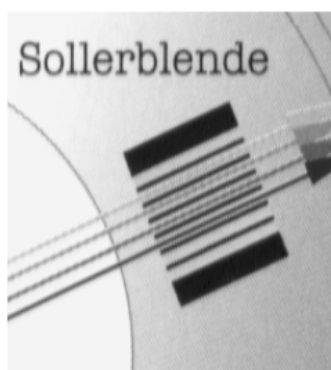


- Soller slit - reduce angular divergence of the incident X-ray beam in the direction  $//$  to goniometer axis (reduce axial divergence)

## Slit assemblies and soller slits

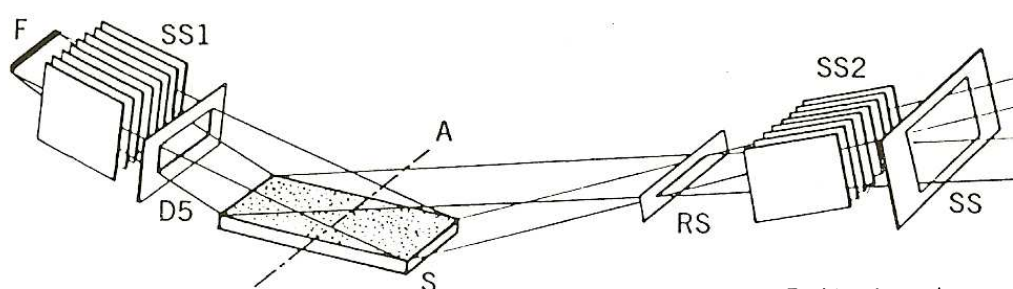
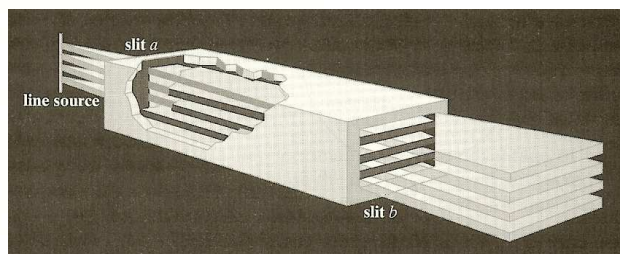
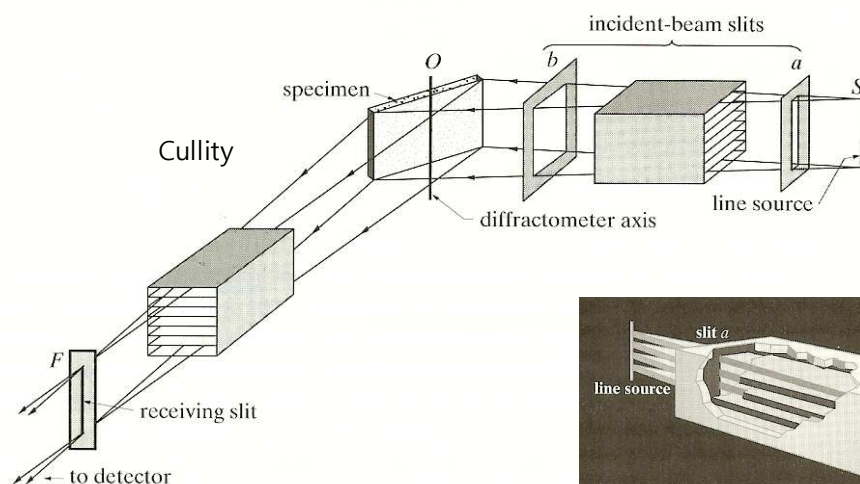


The normal slit consists of two blades, limiting the beam width. For automatic changing of the slit width, turnable edges are used.



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## Soller slit

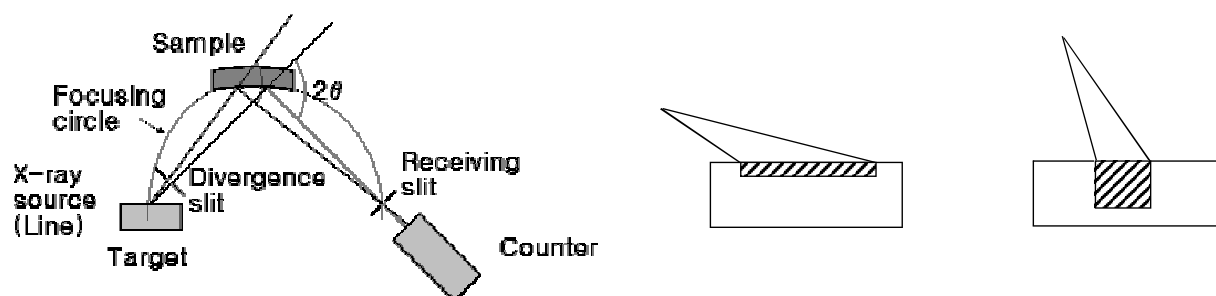


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## Slit

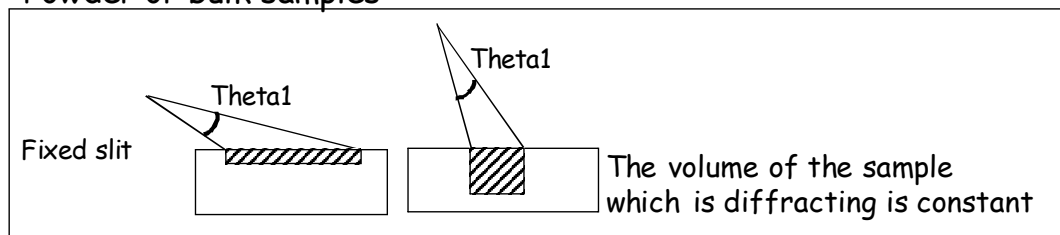
- In case the line intensities are to be compared over the whole range of  $2\theta$ , the same divergence must be used and specimen must be larger than the beam at all angles
- Variable divergence slit → irradiated area constant at all  $2\theta$  angles
- Fixed divergence slit → irradiated volume constant at all  $2\theta$  angles
- Receiving slit defines the width of beam admitted to the detector. Increase of receiving slit → increase of maximum intensity, loss of resolution



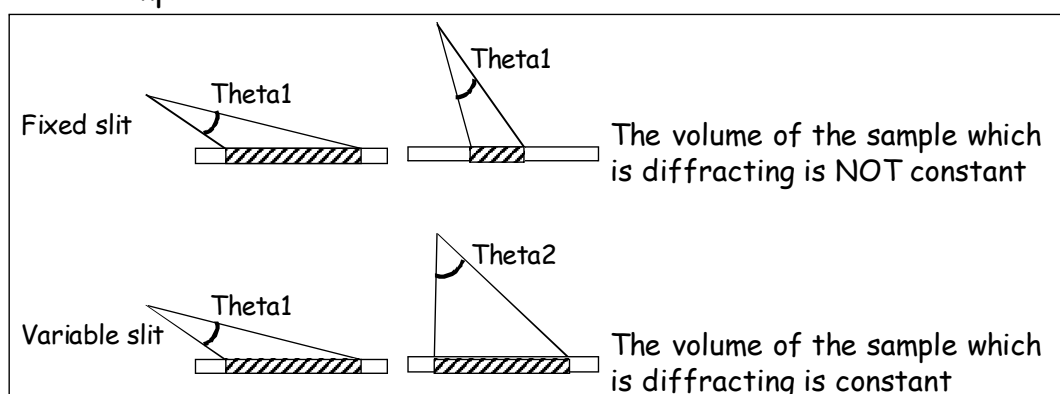
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## Variable slit vs. Fixed slit

### Powder or bulk samples



### Thin samples



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# Monochromators

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## Monochromatic radiation

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- Problems caused by polychromatic nature of diffracted beam & variability of angular dispersion
- XRD pattern from multiple wavelength, or that from unknown wavelength → difficulty in interpreting the pattern
- Why monochromatic beam is wanted? - we want to obtain experimental pattern from a single wavelength
- Monochromatization by reducing the intensity of white radiation & by eliminating undesirable characteristic wavelengths from X-ray spectrum
  - ✓  $\beta$  filter
  - ✓ Diffracted beam monochromator
  - ✓ Primary beam monochromator
  - ✓ Pulse height selection using proportional counter
  - ✓ Use of solid state detector (high resolution energy resolving detector)

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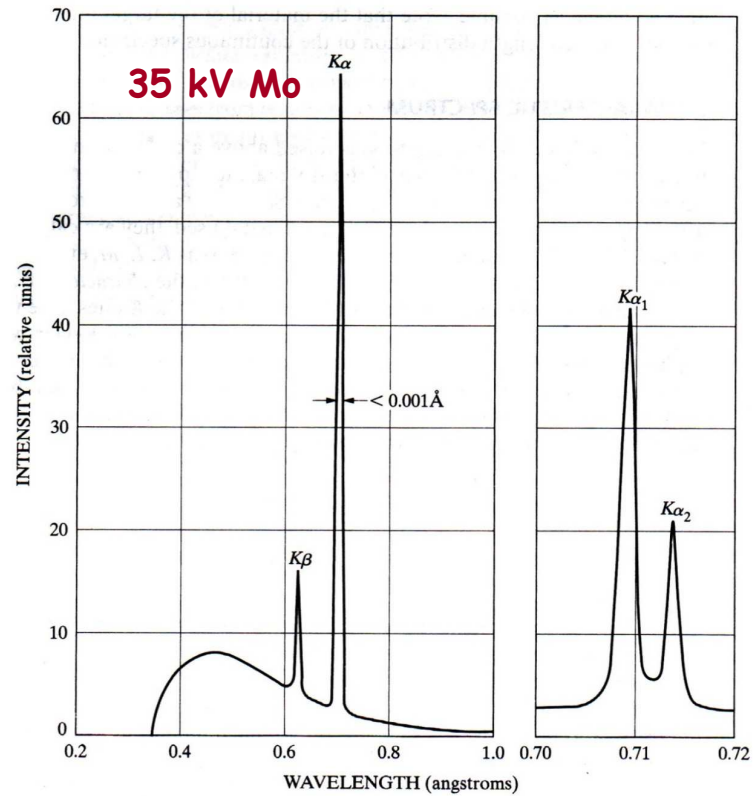
## X-ray spectrum of molybdenum

$2p \rightarrow 1s$

$\alpha_1, \alpha_2$  doublet

$\beta_1, \beta_3$  doublet

$3p \rightarrow 1s$

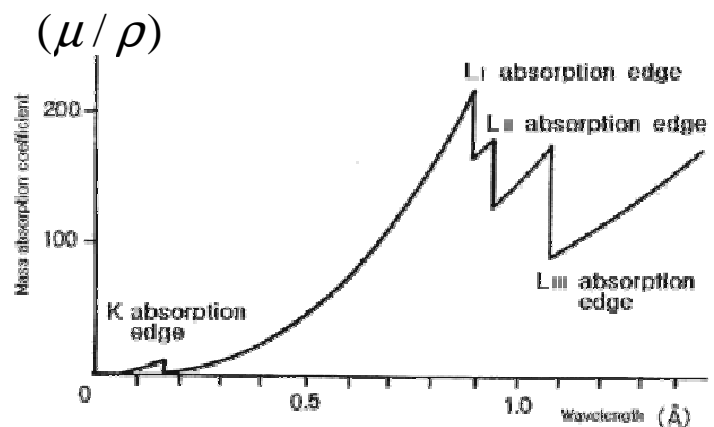
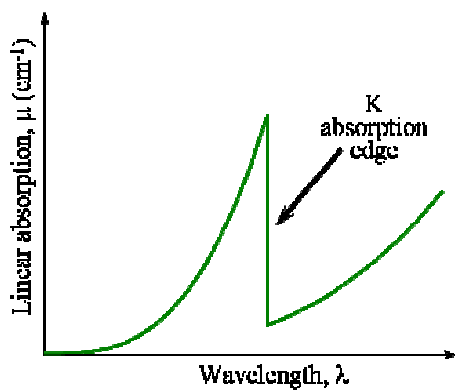
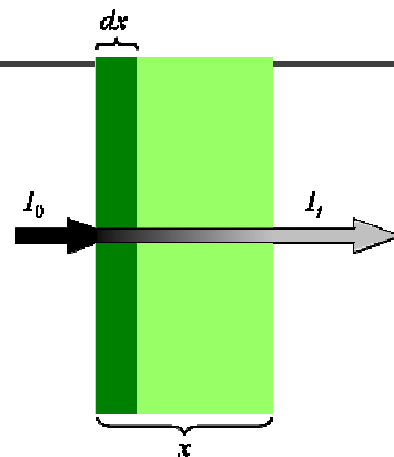


## Absorption of X-rays

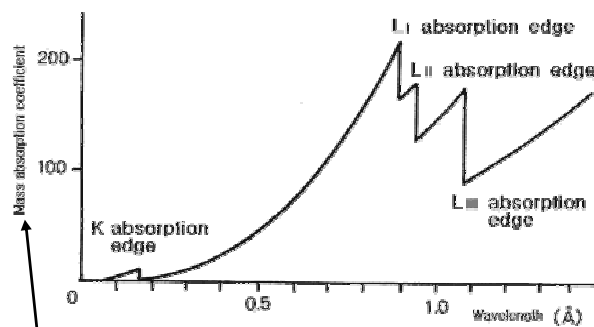
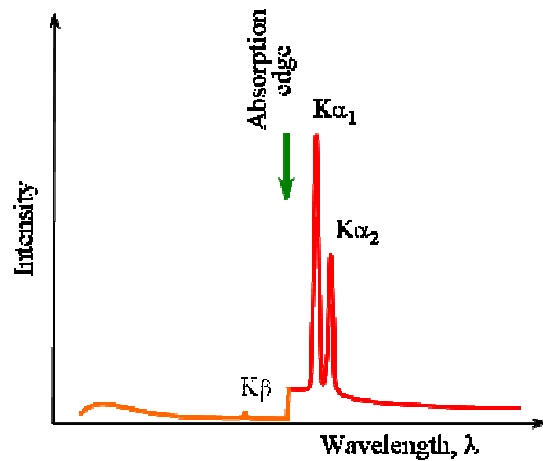
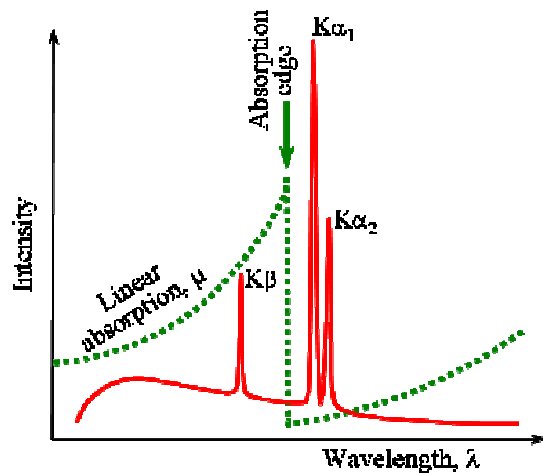
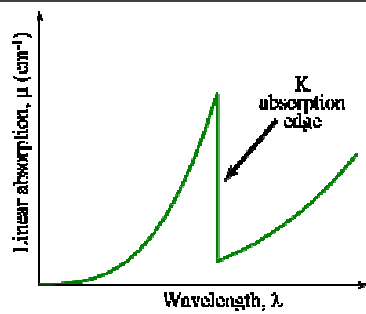
$$I_x = I_0 e^{-(\mu/\rho)\rho x}$$

$\mu$  linear absorption coefficient

$\mu/\rho$  mass absorption coefficient



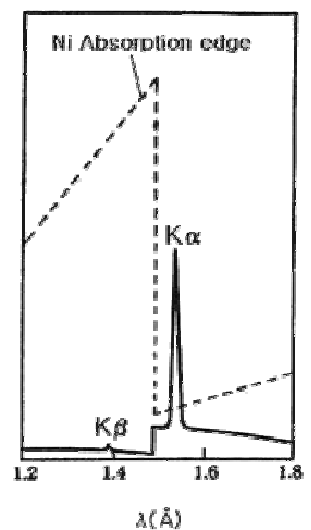
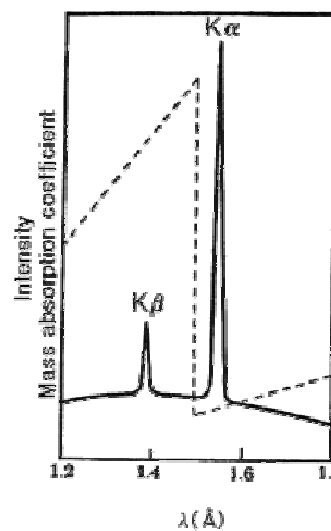
## $\beta$ -filter



$$(\mu / \rho)$$

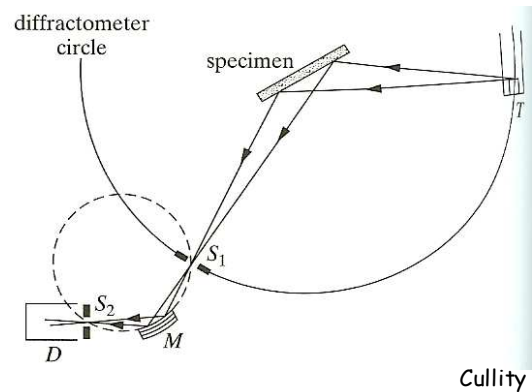
$$I_x = I_0 e^{-(\mu / \rho) \rho x}$$

$\beta$ -filter  
 $K_\alpha$  vs.  $K_\beta$



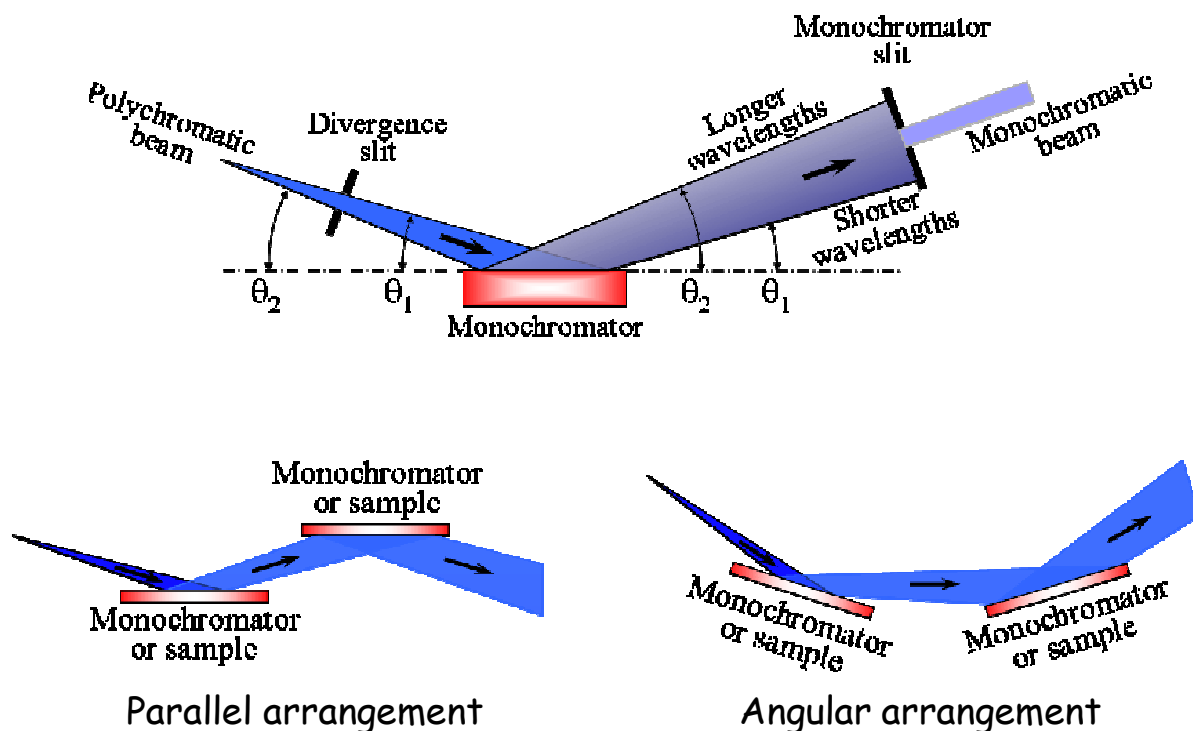
## Monochromators

- Ways to reduce BKG
  - ✓ Pulse-height analyser
  - ✓ Diffracted beam monochromator → suppress BKG radiation originating at the specimen (fluorescent radiation, incoherent scattered radiation)
  - ✓ Balanced filter
- Monochromator can be placed in diffracted beam in diffractometer (not in the area detector)
- Incident beam monochromator →  $L_p$  factor has to be changed (has to include contribution from the diffraction at the monochromator)
- LiF, graphite, Si, Ge, SiO<sub>2</sub> (quartz), etc



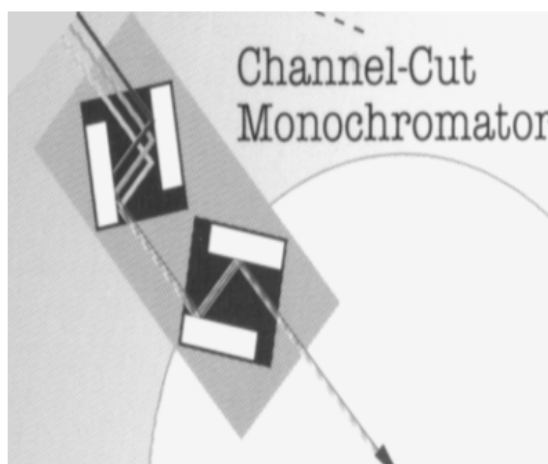
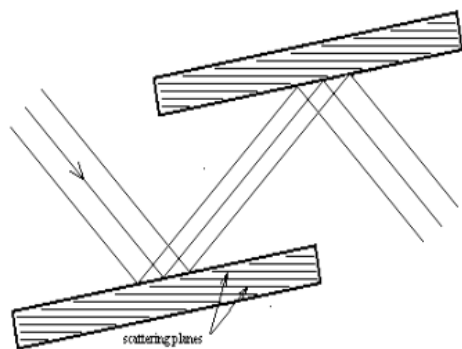
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## Single crystal monochromator

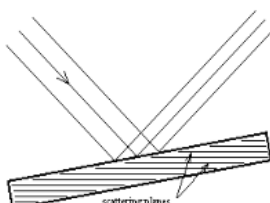
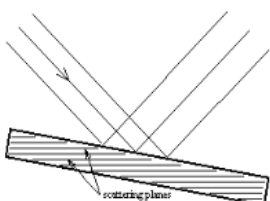
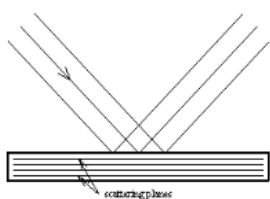


## Multi bounce single crystal Monochromators

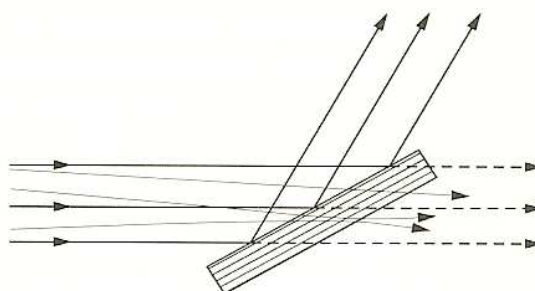
An arrangement of two or four plane crystals provides a beam with very low wavelength dispersion and divergence. Using special channel cut crystals, a high brilliance source is yielded.



## Plane unbent crystal Monochromators

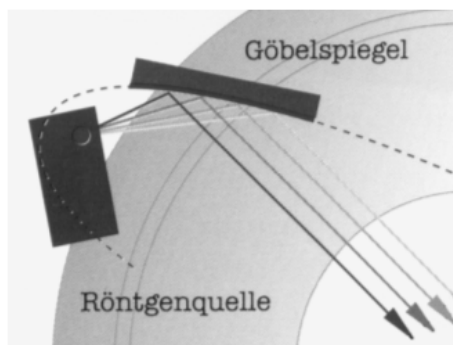
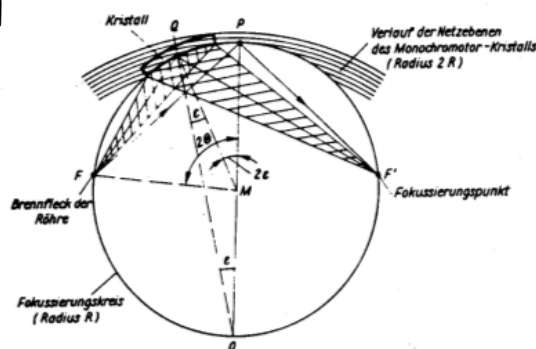


- A single crystal may reflect the primary beam, according to Bragg's law, if well aligned.
- It will reject radiation from the wrong direction or the wrong wavelength. → intensity low
- A perfect single crystal will show high resolution in angles or wavelength.
- A poly-domain crystal will show low resolution.
- The better the resolution, the more carefully it must be aligned.



## Bent crystal primary Monochromators

A monochromator of type Johannson is special cut and bent single crystal. It enables the focal spot or the divergent primary beam to be focused to a point again.

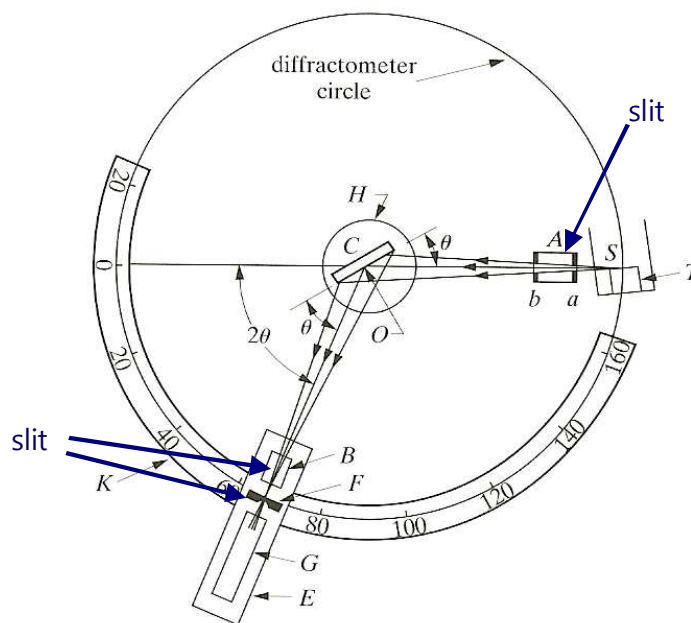
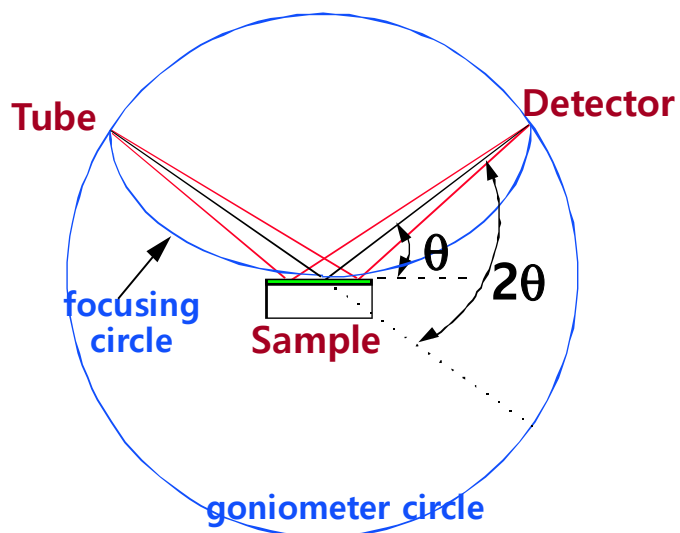


The Göbel Mirror is bent like a parabola. The divergent beam emitted by the X-ray tube is converted into a parallel one illuminating the sample. Mounted in the diffracted beam, the beam off the mirror is reflected into the receiving slit.

# X-ray Diffractometer

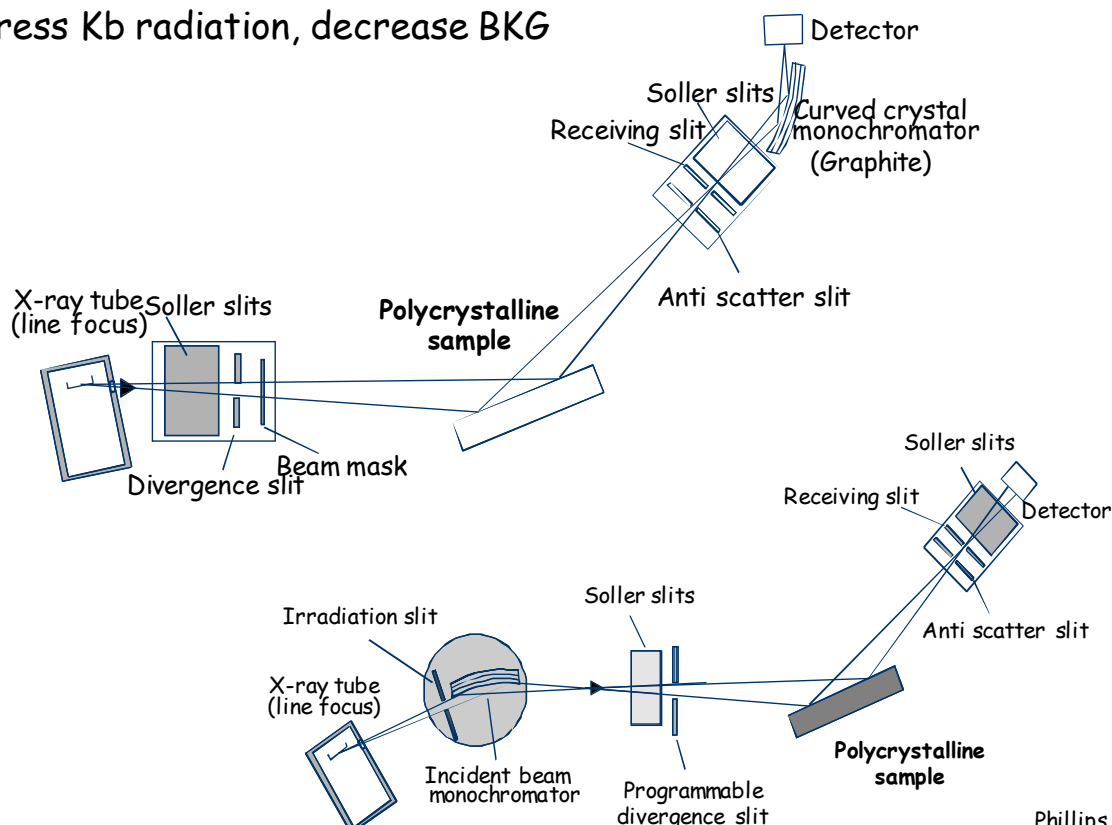


## Bragg-Brentano geometry (parafocusing geometry)

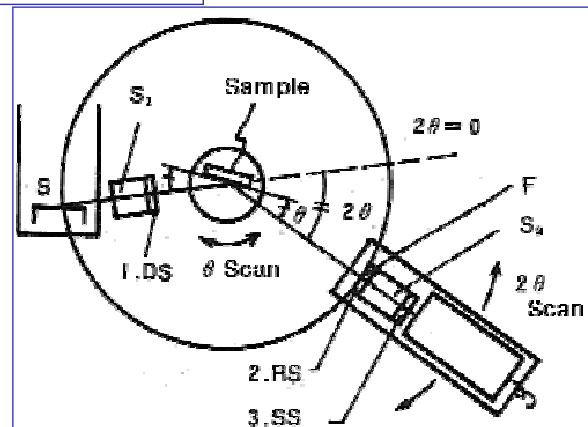
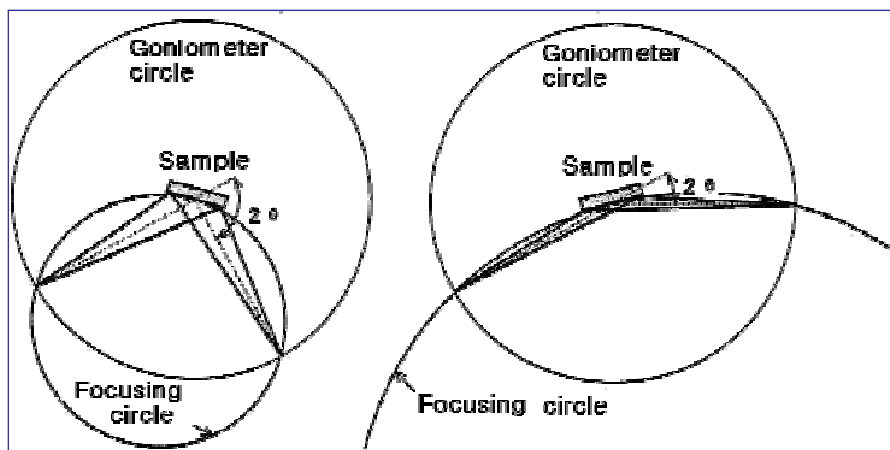


## X-ray diffractometer > Bragg-Brentano

- monochromator or filter in diffracted beam
- suppress  $K\beta$  radiation, decrease BKG

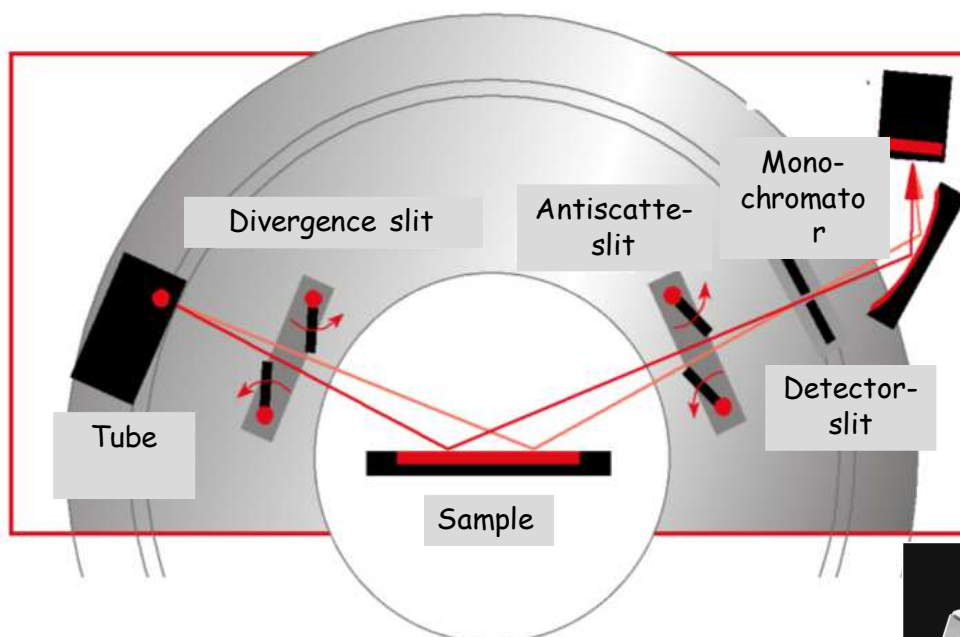


## Bragg-Brentano Geometry (parafocusing geometry)

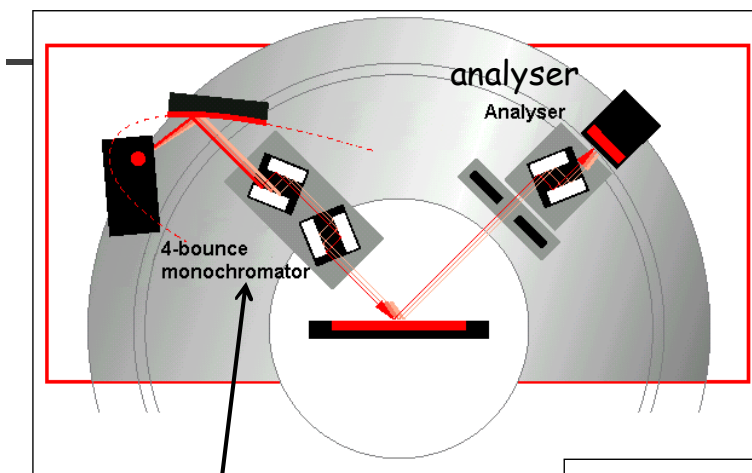
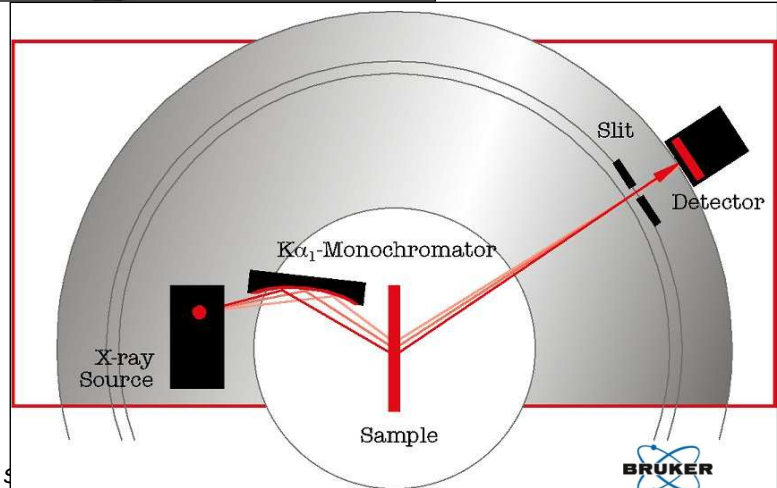
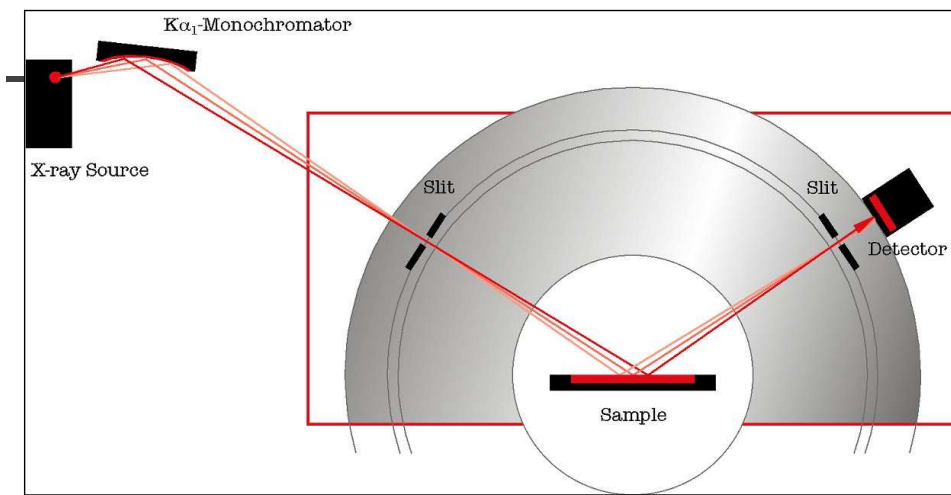


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## The Bragg-Brentano Geometry

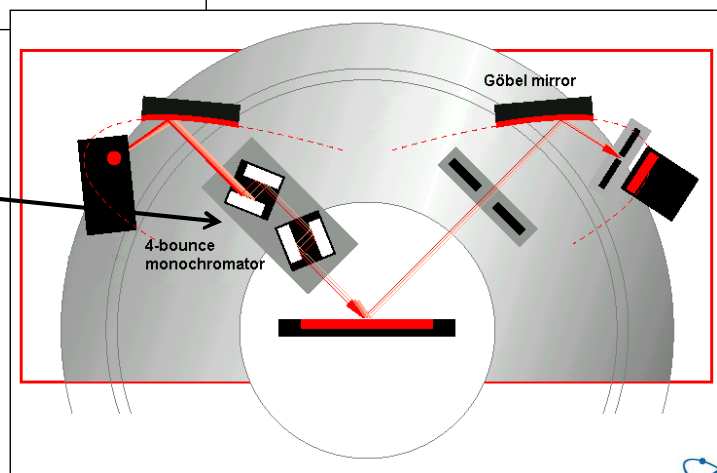


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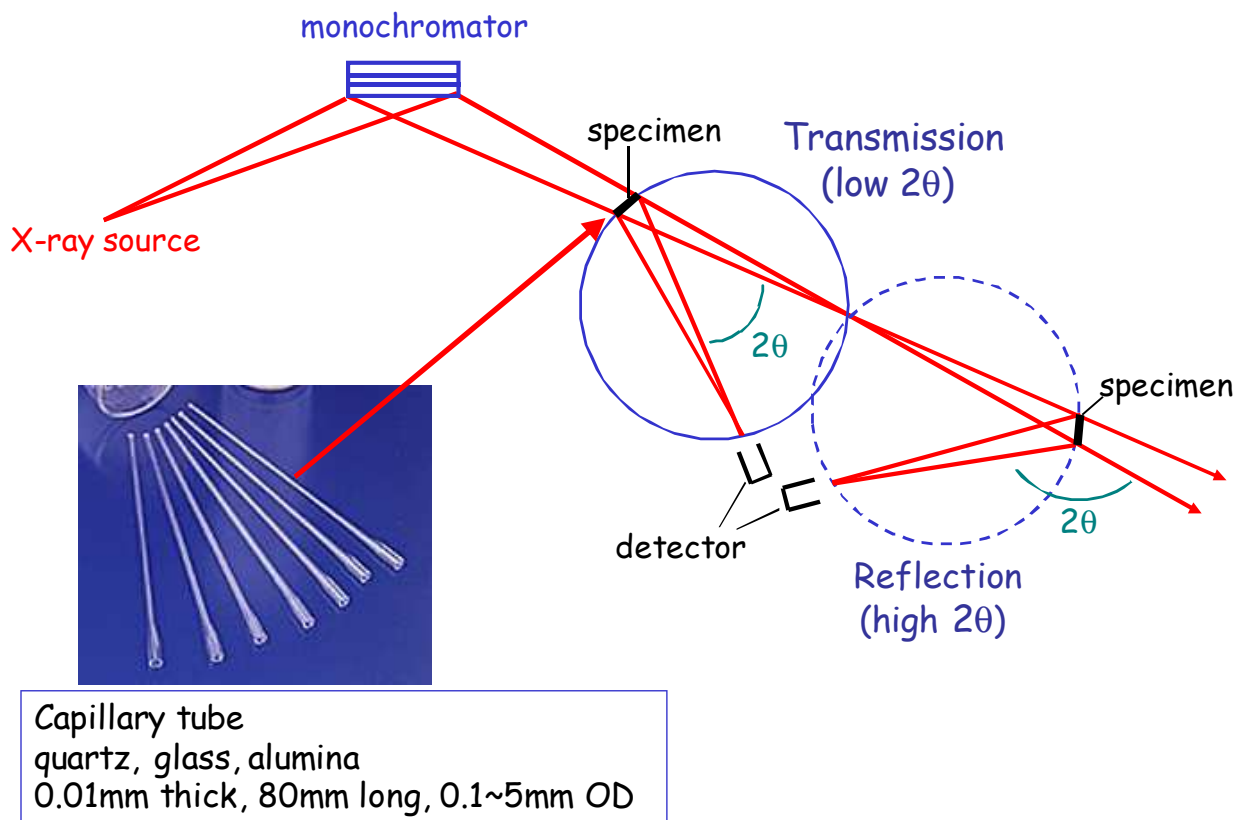


4-bounce  
monochromator

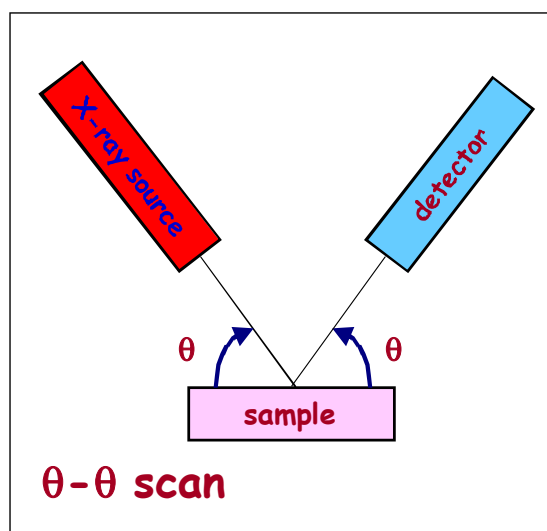
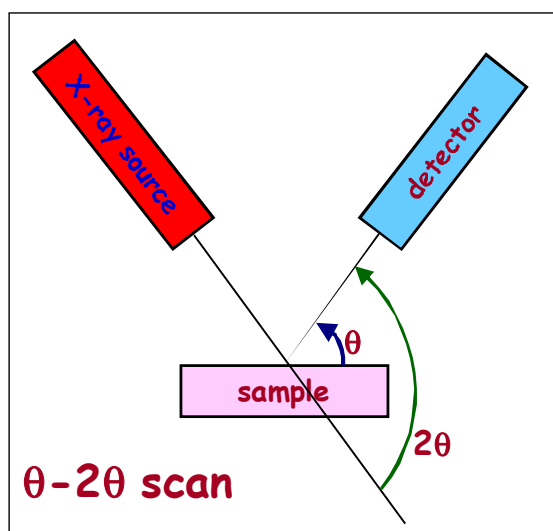
Göbel Mirror



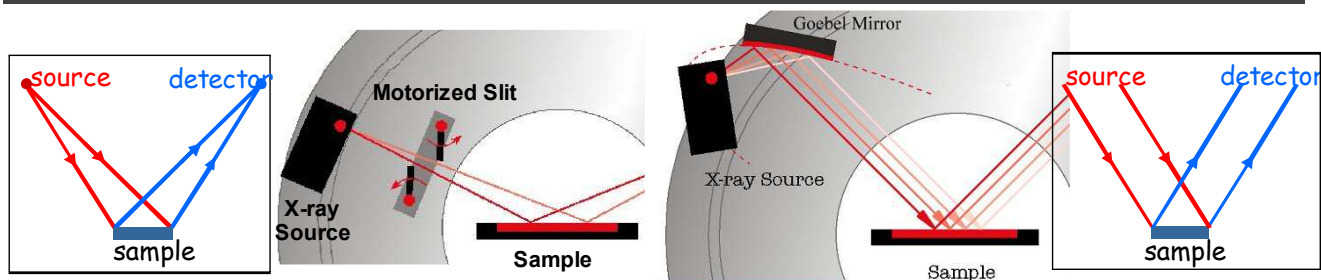
# Guinier Diffractometer



## $\theta$ - $2\theta$ scan vs. $\theta$ - $\theta$ scan

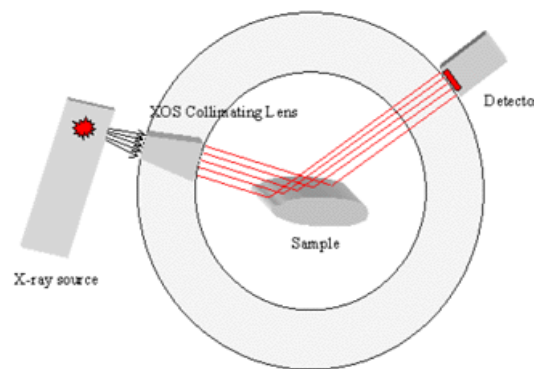
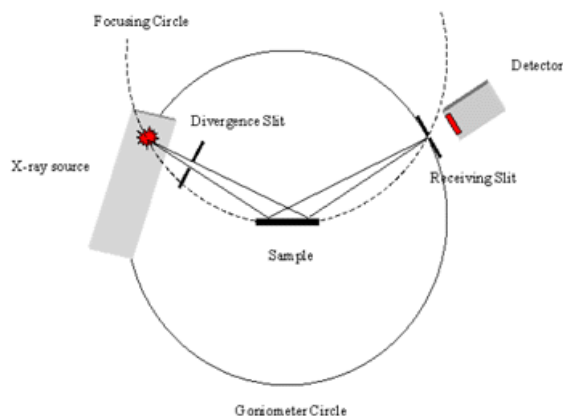


# Bragg-Brentano vs. Parallel Beam Geometry

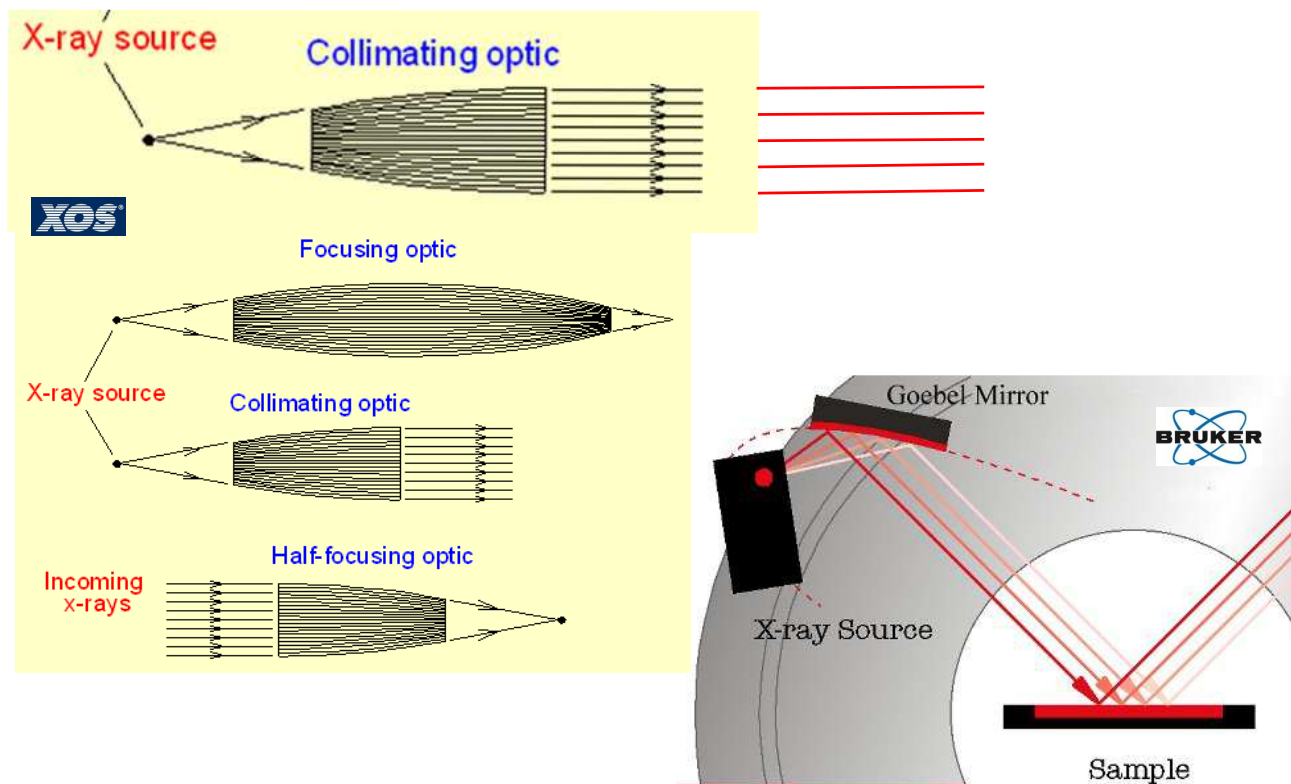


**Bragg-Brentano Geometry**  
(para-focusing geometry)

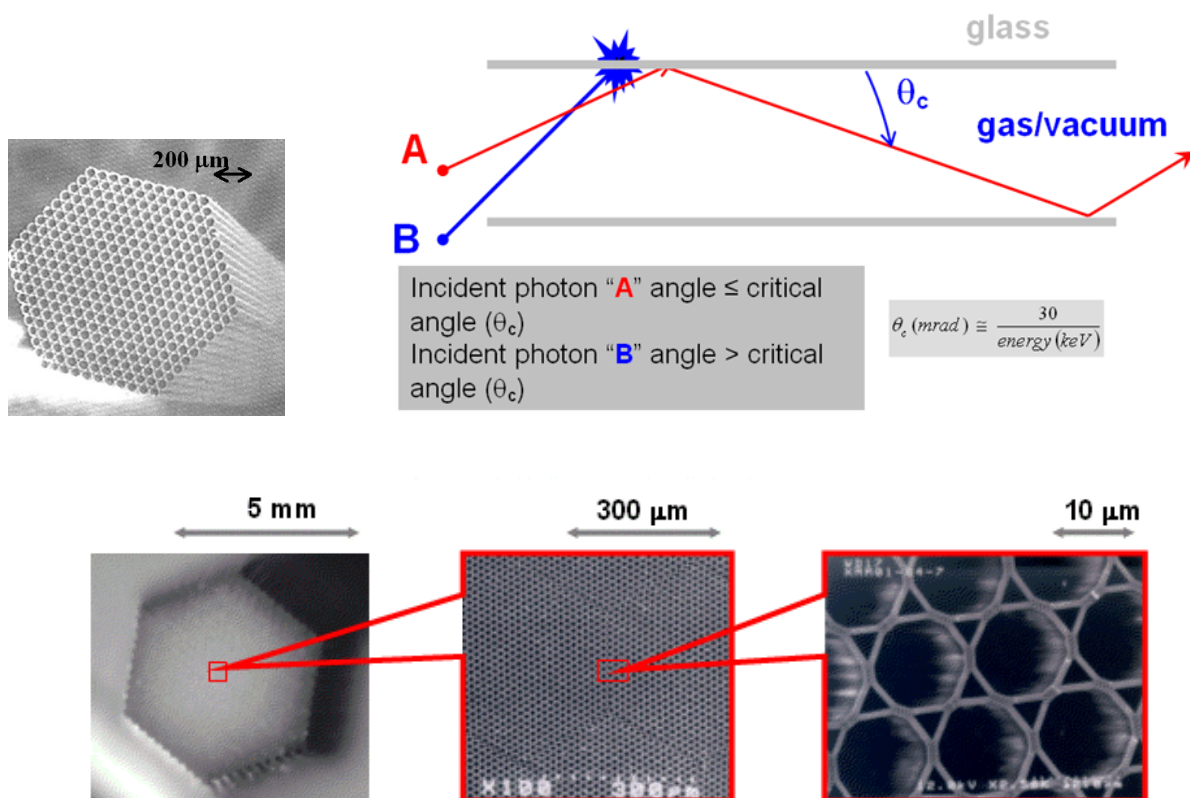
**Parallel Beam Geometry**  
generated by **Göbel Mirrors**



## Parallel beam optics → no sample displacement error







## Parallel beam geometry can be used for

- analysis of samples with non-flat surfaces, e.g. corrosion on pipes
- samples you would prefer not to grind to a powder, e.g. jewelry, archaeology or forensic samples



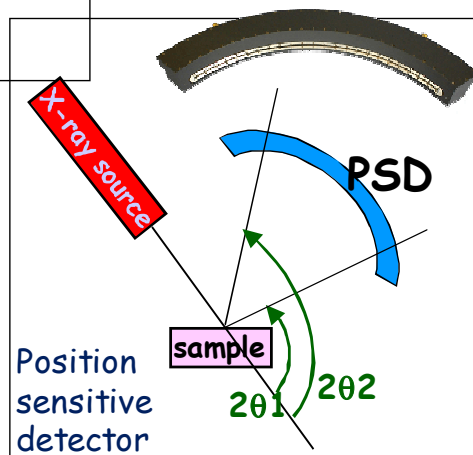
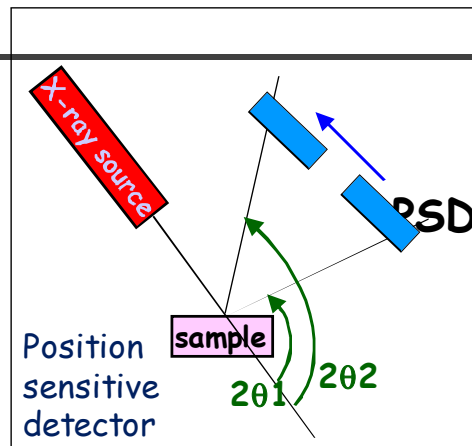
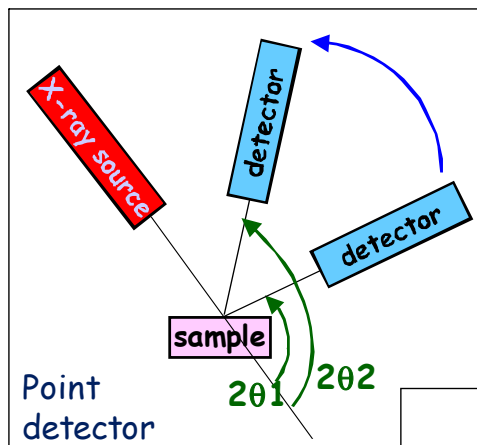
Sodalite  
Bracelet



Vesuvianite  
Pebble

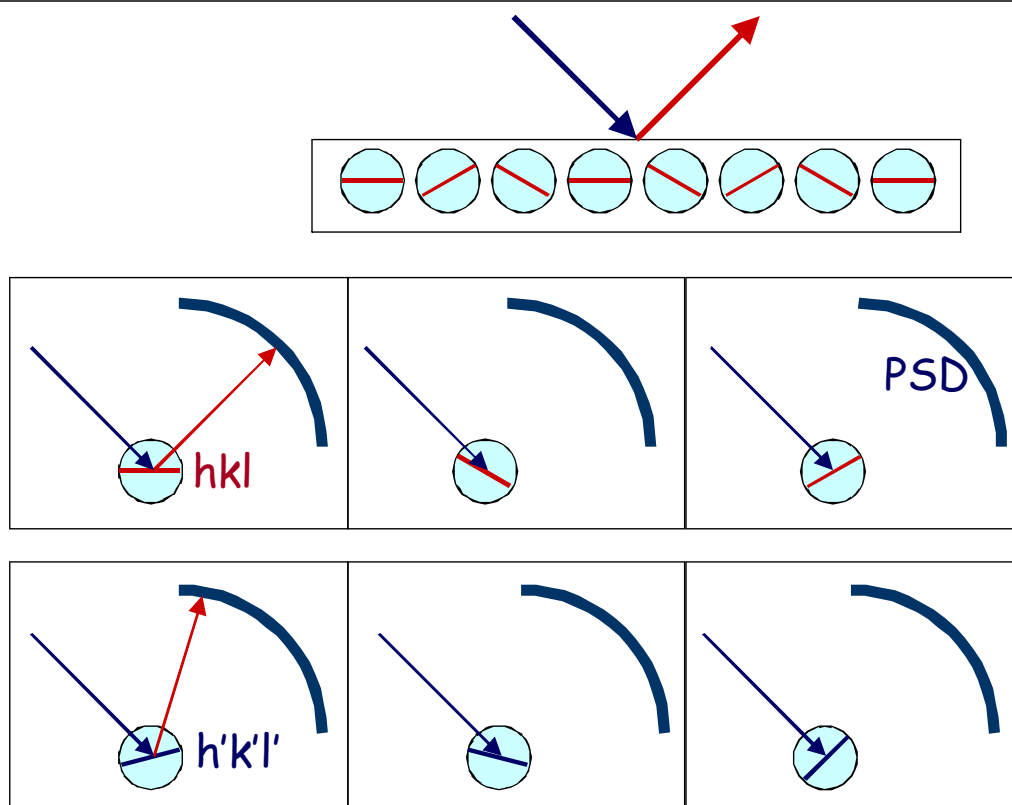
- measure thermal expansion and contraction when using the heating/cooling stage
- grazing incidence diffraction (GID) of layers on substrates
- reflectometry for thin film thickness and roughness

## Point, Line, & Area detector

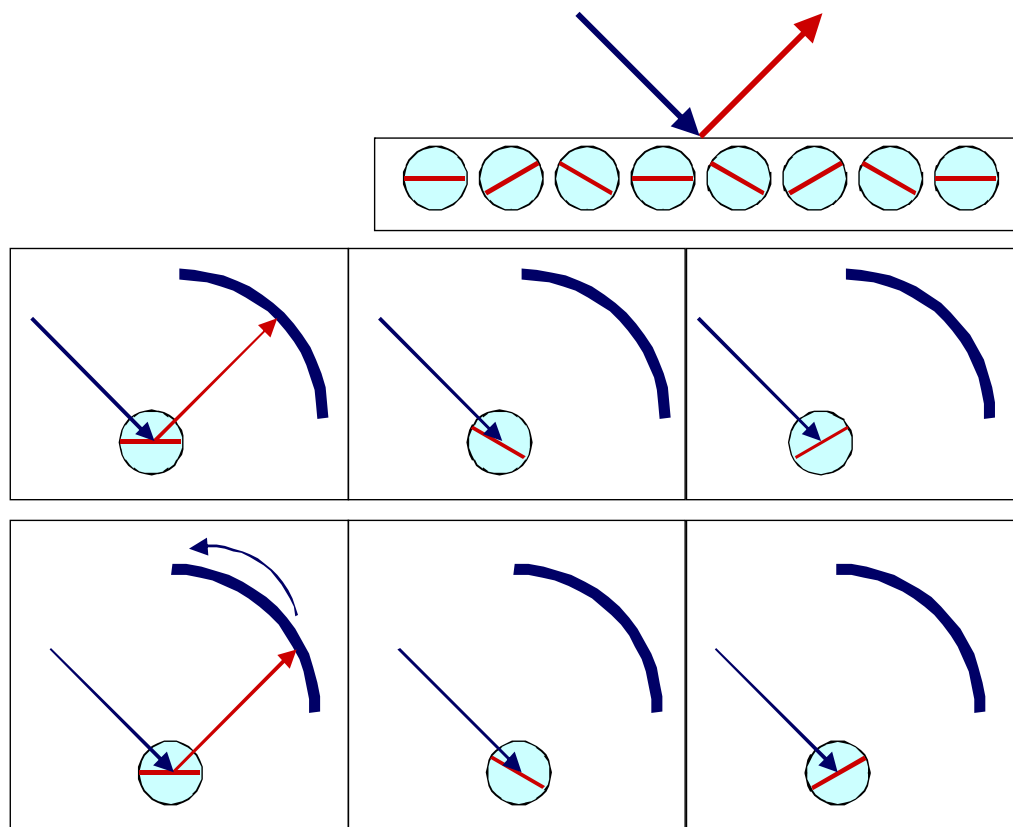


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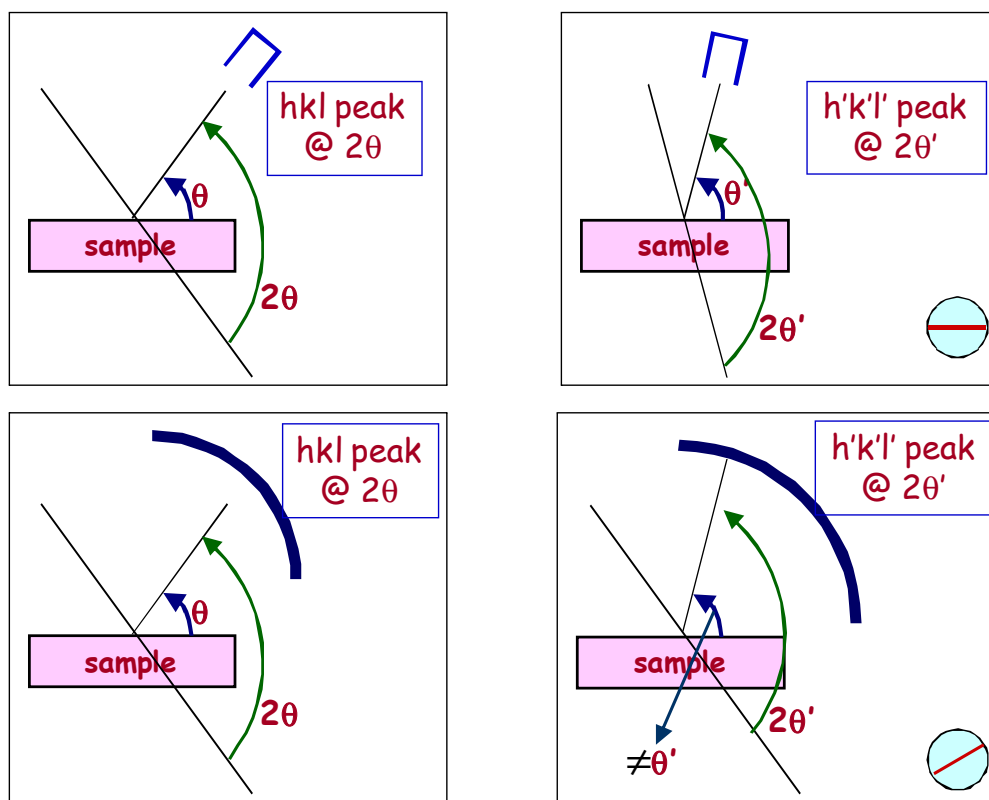
## Line detector, PSD



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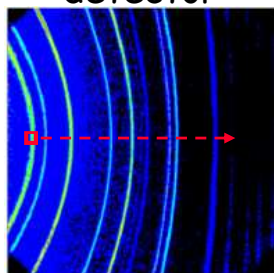


## Point detector vs. Line detector



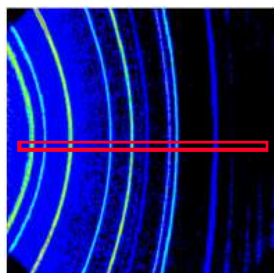
## Point, Line, and Area detector

Scintillation detector



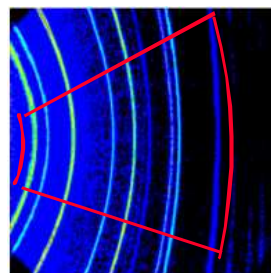
- ✓ small spot measured
- ✓ scan necessary
- ✓ long collection time

Line detector (PSD)

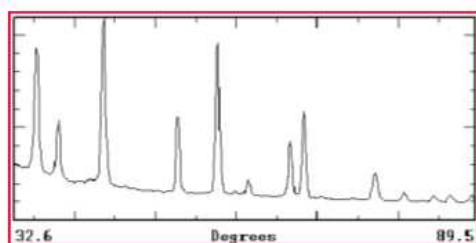


- ✓ large  $2\theta$  range measured simultaneously
- ✓ medium collection time

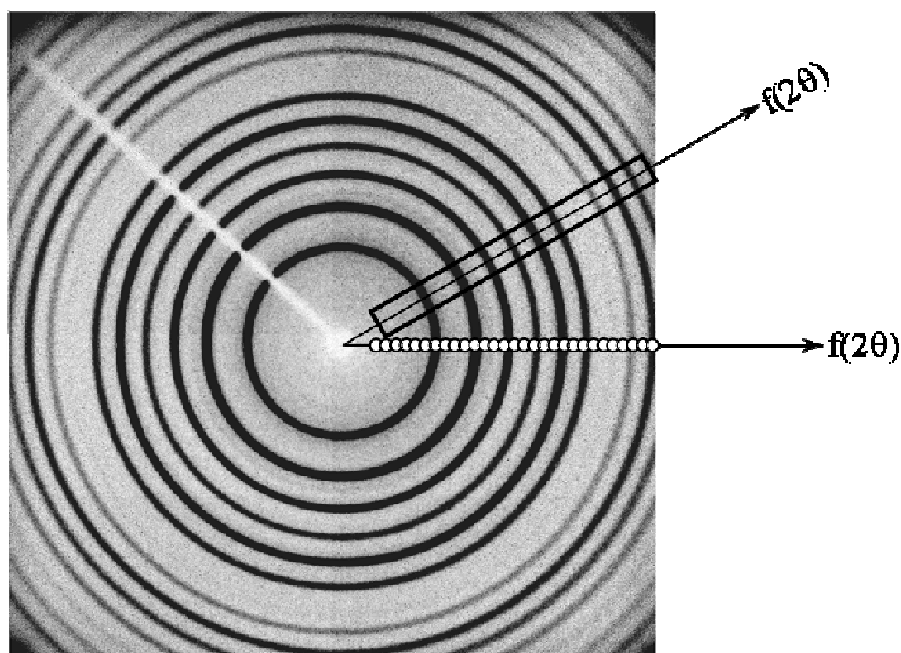
Area detector



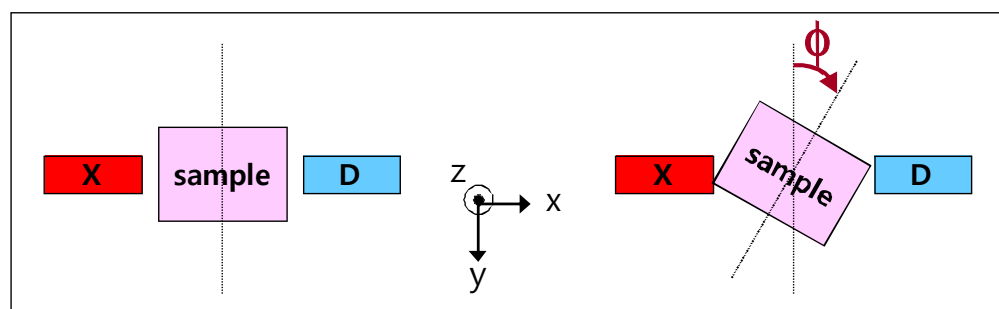
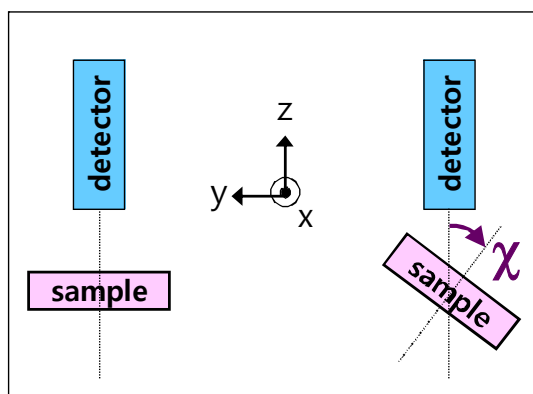
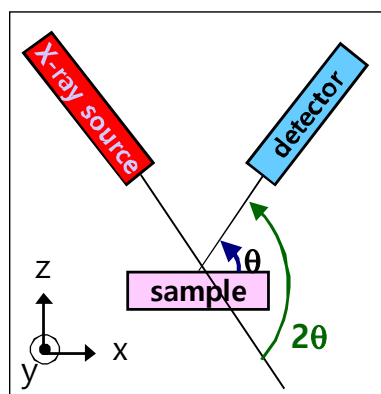
- ✓ large  $2\theta$  and  $\chi$  range measured simultaneously
- ✓ measurement of oriented samples
- ✓ very short collection times
- ✓ intensity versus  $2\theta$  by integration of the data



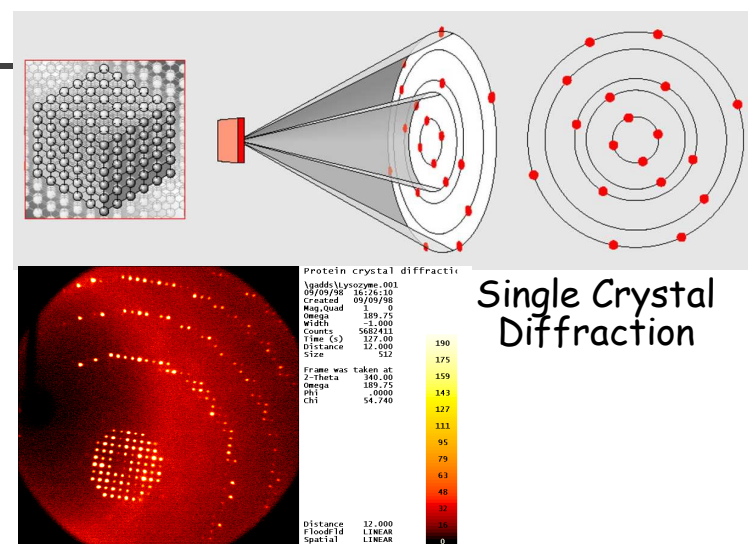
## Point, Line, and Area detector



## Angles - $\theta(\omega)$ , $2\theta$ , $\phi$ , $\chi$

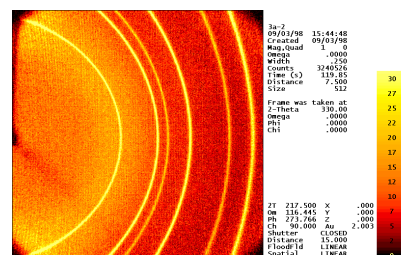


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Single Crystal Diffraction

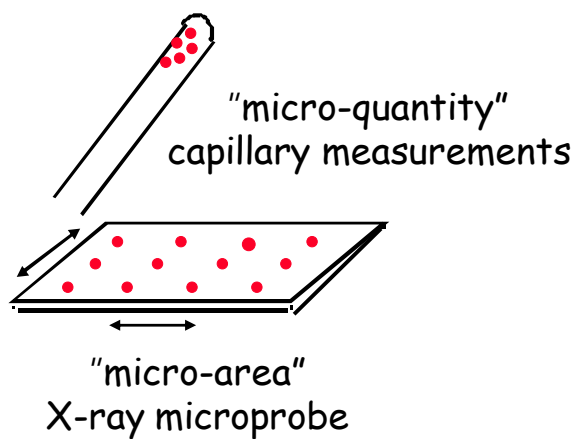
Powder Diffraction



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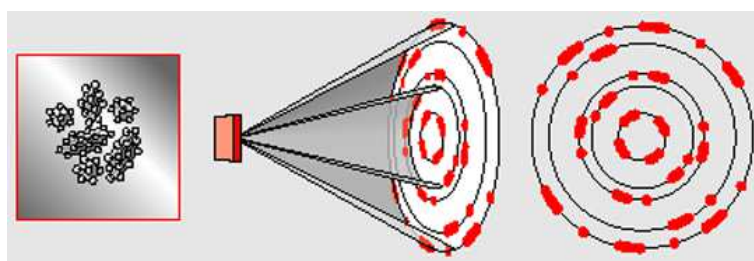
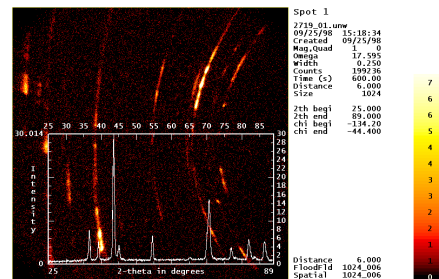
## Microdiffraction



- qualitative phase analysis
- micro-texture
- quick point-and-shoot operation

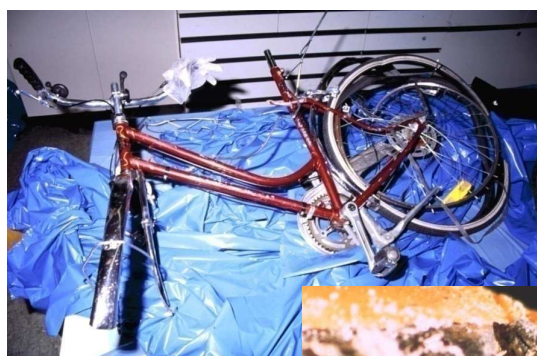


Inspection of a gold pad

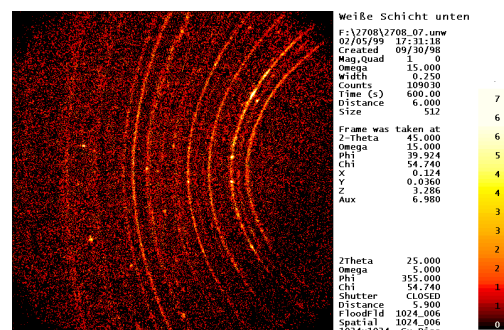
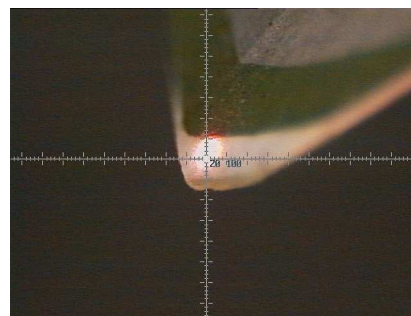


## Forensic Application

### Fatal Bicycle Accident Collection of Evidence



traces of car paint  
found on the bicycle



Dr. W. Kugler  
Landeskriminalamt  
Baden-Württemberg  
Stuttgart, Germany





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# Detector

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## Detectors

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- X-ray detector = transducer + pulse formation circuit
- Transducer - convert the energies of X-ray photons to electric currents
- Pulse formation circuit - convert current into voltage pulses that are counted/integrated by counting equipment
- Transducer = detector or counter
  
- Gas proportional counter, scintillation counter, Si(Li) detector, intrinsic germanium detector → all use the ability of X-rays to ionize matter

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## Characteristics of detector

### ➤ Quantum efficiency

- ✓ How efficiently it collects x-ray photons and then converts them into a measurable signal

### ➤ Linearity

- ✓ Linear when there is a linear dependence between the photon flux and the rate of signals generated by the detector per second
- ✓ Dead time

### ➤ Proportionality

- ✓ How the size of the generated voltage pulse is related to the energy of the x-ray photon

### ➤ Resolution

- ✓ Ability to resolve x-ray photons of different energy and wavelength

**Table 5.3. Properties of Common X-ray Detectors**

Property	Scintillation			Xe Sealed Gas			Si(Li)		
	Cr	Cu	Mo	Cr	Cu	Mo	Cr	Cu	Mo
Quantum efficiency (%)	60	98	100	90	90	75	90	95	80
Linearity—loss at 40,000 c/s	Less than 1%			Up to 5%			Up to 50%		
Proportionality	Very stable			Pulse shift at high c/s			Pileup, etc., at moderate c/s		
Resolution (%)	55	45	31	17	14	10	3	2	1

## Photographic film

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- Silver halide → metallic silver, when exposed to x-ray photons
- Once developed (darkened), further incoming X-rays can change nothing  
→ loss of information (**dead time** in electronic counters)
- Film darkening is proportional to the intensity of exposing X-rays over  
LINEAR RANGE of the film
- When measuring intense sources
  - ✓ (1) Have to reduce X-ray intensity with filters or reduce incident beam flux
  - ✓ (2) extend linear range of the film
- Low proportionality range, limited spatial & energy resolution

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## Detector

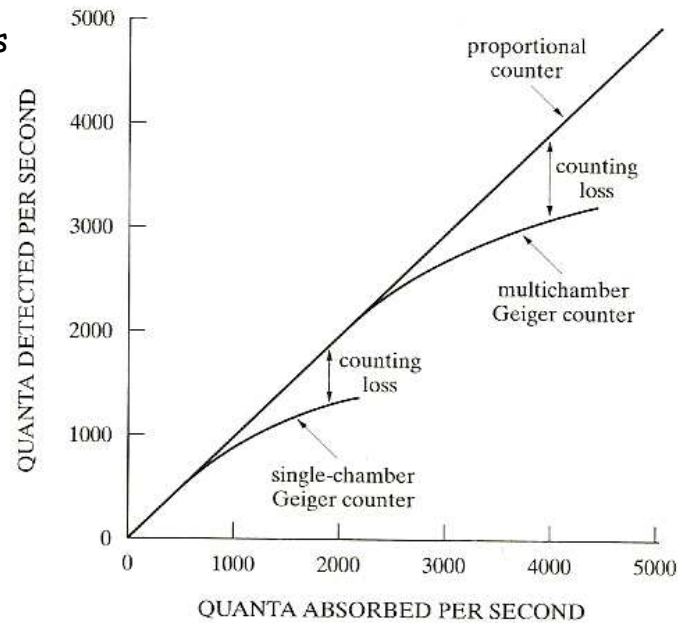
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- all use the ability of X-rays to ionize matter
  - ✓ Matter = gas → Proportional, Geiger
  - ✓ Matter = solid → Scintillation, semiconductor
- Proportional
- Geiger
- Scintillation
- Semiconductor

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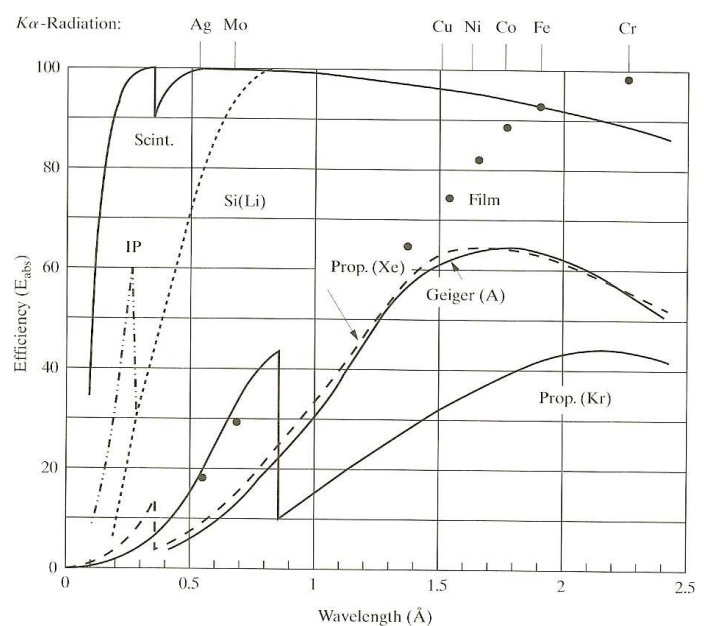
## Counting loss

- When time interval between pulses is very small, adjacent pulses may not be counted as separate pulses  
→ counting loss begins
- Resolving time ( $t_s$ )- minimum time between two resolvable pulses



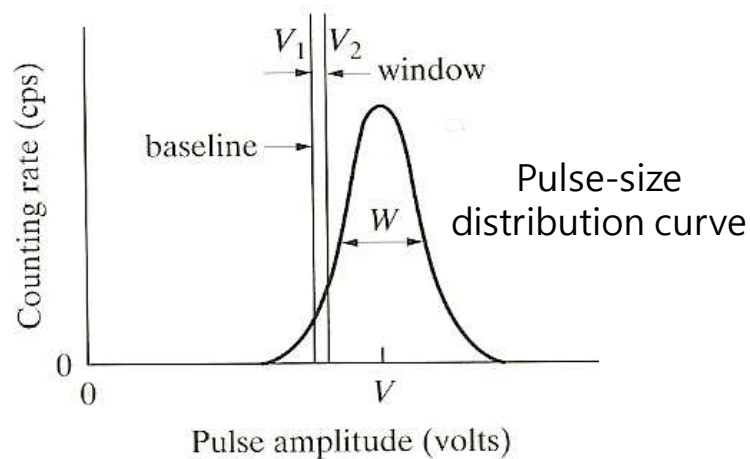
## Counting efficiency

- Efficiency of detector in collecting radiation incident upon it
- Most detectors designed for XRD are optimized for the measurement of Cu Ka radiation. Loss of efficiency can result when different  $\lambda$  is used.



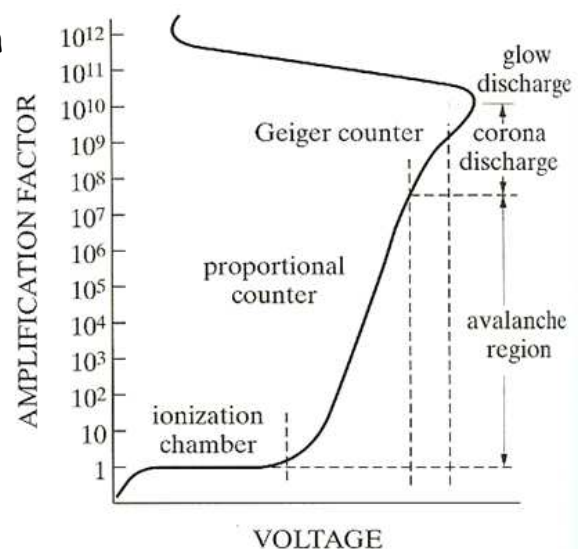
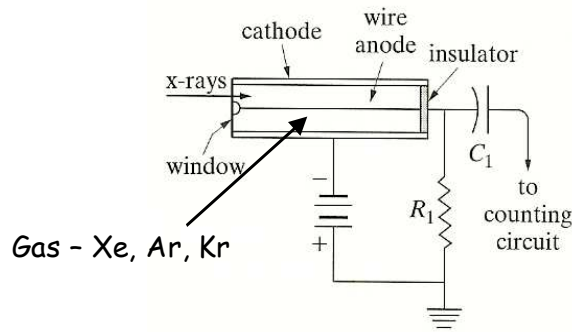
## Resolution

- A measure of detector's ability to resolve two X-ray photons of different energy
- Size of voltage pulses produced by detectors are proportional to the energy of the x-ray quantum absorbed
- Resolution  $R = W/V$



## Proportional counters

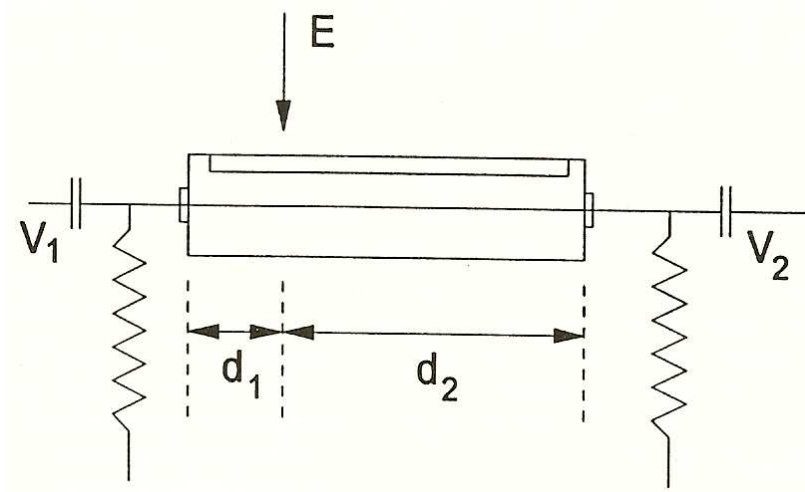
- Size of pulse  $\propto$  energy of X-ray quantum absorbed  $\rightarrow$  X-ray quanta of different energies can be distinguished
- Gas is ionized by incoming X-ray
- $e^- \rightarrow$  anode, positive ion  $\rightarrow$  cathode (cylindrical metal shell)
- multiple ionization  $\rightarrow$  gas amplification



## Position sensitive proportional counter

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- Increased speed of data acquisition
- Measure "rise time" (rate at which a pulse develops) at each end of the wire → detect position can be located
- Angular resolution not very high



## Geiger counter

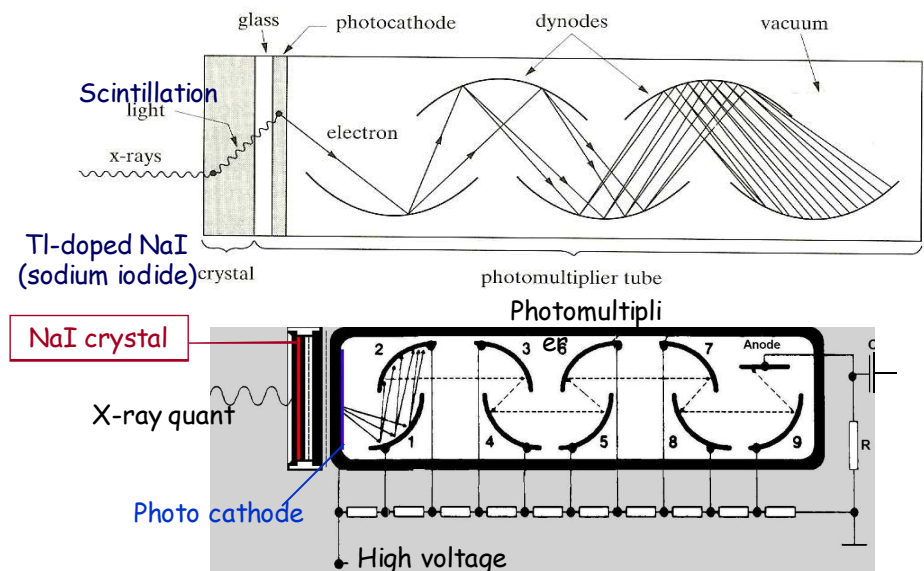
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- Very high voltage in a proportional counter → Geiger counter
- Gas amplification factor much larger than proportional counter
- All pulses have the same size, regardless of the energy of X-ray quanta
- Cannot count at high rates without losses → seldom used in diffractometry



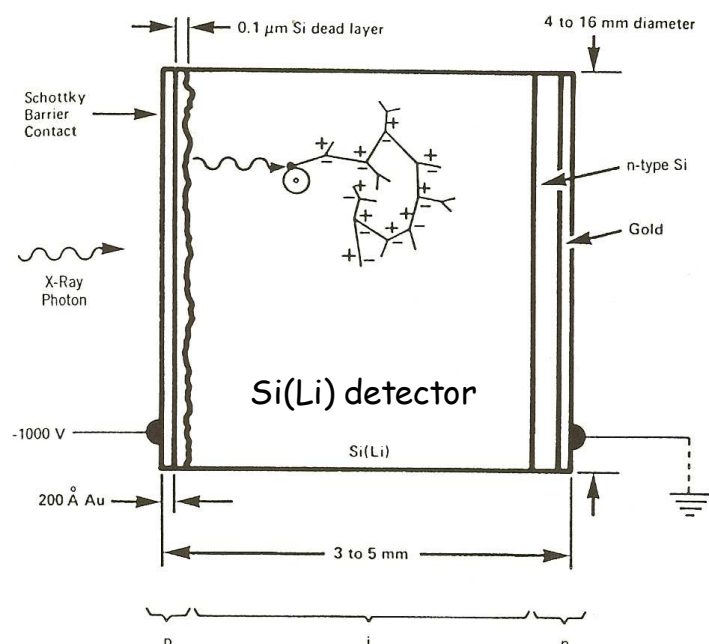
## Scintillation detector

- X-ray can cause certain substances to fluoresce visible light
- Amount of light  $\propto$  emitted X-ray intensity
- Pulses produced  $\propto$  energy of X-ray quanta
- Difficult to discriminate between X-ray quanta of different energies  $\rightarrow$  energy resolution not great

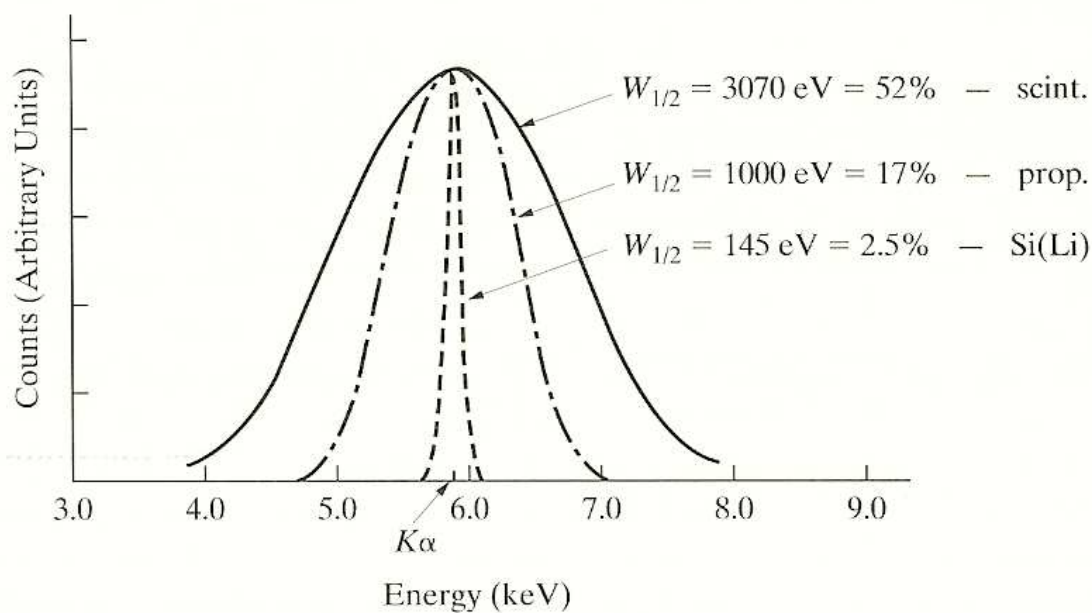


## Semiconductor detector

- Best energy resolution
  - ✓ Produces pulses proportional to the absorbed X-ray energy with better energy resolution than any other detector
- Si(Li), Ge(Li), HPGe
- Need LN2 cooling



## Pulse-height distribution curves



## Pulse height selection (PHS)

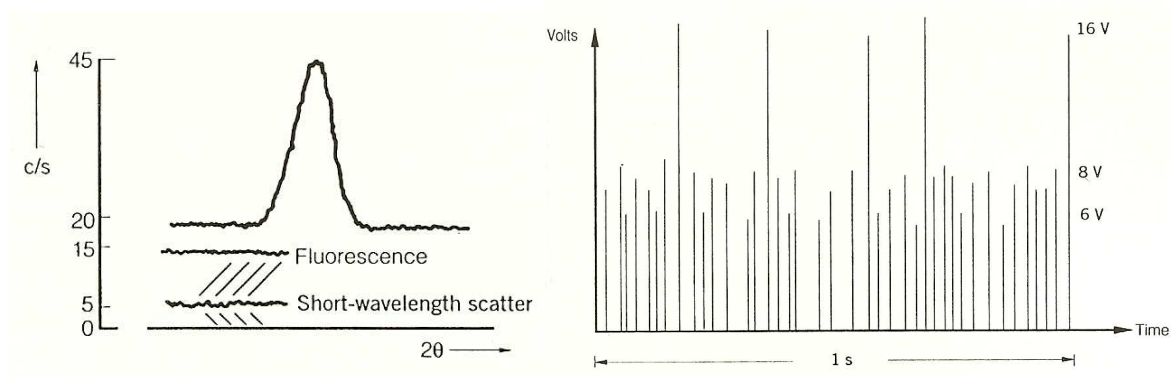
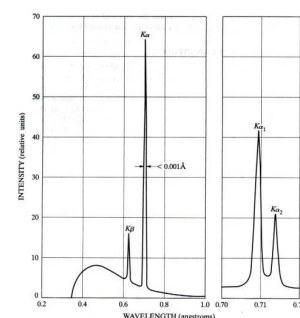


Figure 5.8. The pulse height selector.

- Different energy  $\rightarrow$  different size of voltage pulse  $\rightarrow$  can be electronically discriminated --- PHS, pulse height analyzer (PHA)
- Can remove such effects as sample fluorescence & BKG that may arise from short wavelength X-rays from X-ray tube continuum that pass the b filter



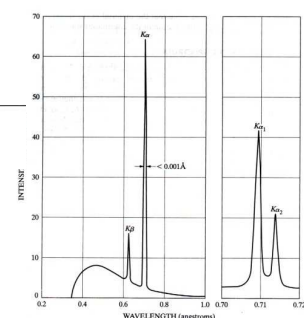
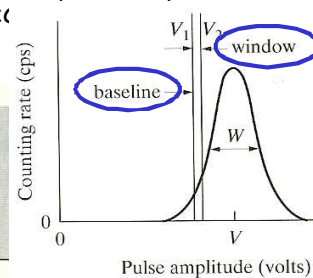
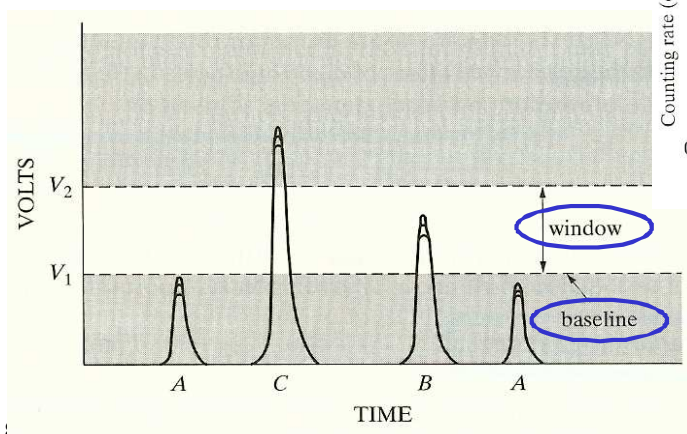
## Pulse height selection (PHS)

- Proportional, scintillation semiconductor detectors
  - "proportional" ; they produce pulses having a size proportional to the energy of the incident X-rays
- If pulses of different size can be distinguished, X-rays of different energies can be distinguished
- Pulse-height discriminator
- Single-channel pulse-height analyzer
- Multi-channel pulse-height analyzer (MCA)

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## Pulse height analysis

- Pulse-height discriminator
  - ✓ Reject any pulses smaller than  $V_1$
- Single-channel pulse-height analyzer
  - ✓ Only pulses having sizes between  $V_1$  &  $V_2$  can pass
  - ✓ Can reduce BKG of diffraction pattern by excluding short I white radiation
- Multi-channel pulse-height analyzer (MCA)
  - ✓ Can separate pulses from a detector that is receiving incident radiation of many wavelengths, by sorting pulses acc



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## Pulse height analysis

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- Pulse-height discriminator
- Single-channel pulse-height analyzer
  - ✓ Entire energy range is scanned serially in time by moving channel
- Multi-channel pulse-height analyzer (MCA)
  - ✓ A large number of fixed channels cover the entire range
  - ✓ All channels simultaneously receive the count-rate information appropriate to each channel

